

CC2651P3 SimpleLink™ Single-Protocol 2.4 GHz Wireless MCU With Integrated Power Amplifier

1 Features

Wireless microcontroller

- Powerful 48-MHz Arm® Cortex®-M4 processor
- · 352KB flash program memory
- 32KB of ultra-low leakage SRAM
- 8KB of Cache SRAM (Alternatively available as general-purpose RAM)
- · Programmable radio includes support for 2-(G)FSK, 4-(G)FSK, MSK, Bluetooth® 5.2 Low Energy, IEEE 802.15.4 PHY and MAC
- Supports over-the-air upgrade (OTA)

Low power consumption

- MCU consumption:
 - 2.91 mA active mode, CoreMark®
 - 61 µA/MHz running CoreMark
 - 0.8 µA standby mode, RTC, 32KB RAM
 - 0.1 µA shutdown mode, wake-up on pin
- Radio Consumption:
 - 6.4 mA RX
 - 7.1 mA TX at 0 dBm
 - 9.5 mA TX at +5 dBm
 - 22 mA TX at +10 dBm
 - 101 mA TX at +20 dBm (7x7 package)

Wireless protocol support

- **Ziabee®**
- Bluetooth® 5.2 Low Energy
- SimpleLink™ TI 15.4-stack
- Proprietary systems

High performance radio

- -104 dBm for Bluetooth® Low Energy 125-kbps
- Output power up to +20 dBm with temperature compensation

Regulatory compliance

- Suitable for systems targeting compliance with these standards:
 - ETSI EN 300 328, EN 300 440 Cat. 2 and 3
 - FCC CFR47 Part 15
 - ARIB STD-T66

MCU peripherals

- Digital peripherals can be routed to any GPIO
- Four 32-bit or eight 16-bit general-purpose timers
- 12-bit ADC, 200 kSamples/s, 8 channels
- 8-bit DAC
- **Analog Comparator**
- UART, SSI, I²C, I²S
- Real-time clock (RTC)
- Integrated temperature and battery monitor

Security enablers

- AES 128-bit cryptographic accelerator
- True random number generator (TRNG)
- Additional cryptography drivers available in Software Development Kit (SDK)

Development tools and software

- LP-CC2651P3 Development Kit
- SimpleLink™ CC13xx and CC26xx Software Development Kit (SDK)
- SmartRF™ Studio for simple radio configuration
- SysConfig system configuration tool

Operating range

- On-chip buck DC/DC converter
- 1.8-V to 3.8-V single supply voltage
- -40 to +105°C

Package

- 7-mm × 7-mm RGZ VQFN48 (26 GPIOs)
- 5-mm × 5-mm RKP VQFN40 (18 GPIOs)
- RoHS-compliant package



2 Applications

- 2400 to 2500 MHz ISM and SRD systems ¹ with down to 4 kHz of receive bandwidth
- Building automation
 - Building security systems motion detector, electronic smart lock, door and window sensor, garage door system, gateway
 - HVAC thermostat, wireless environmental sensor, HVAC system controller, gateway
 - Fire safety system smoke and heat detector, fire alarm control panel (FACP)
 - Video surveillance IP network camera
 - Elevators and escalators elevator main control panel for elevators and escalators

- Industrial transport asset tracking
- Factory automation and control
- Medical
- Electronic point of sale (EPOS) Electronic Shelf Label (ESL)
- · Communication equipment
 - Wired networking wireless LAN or Wi-Fi access points, edge router, small business router
- Personal electronics
 - Home theater & entertainment smart speakers, smart display, set-top box
 - Wearables (non-medical) smart trackers, smart clothing

3 Description

The SimpleLink™ CC2651P3 device is a single-protocol 2.4-GHz wireless microcontroller (MCU) supporting Zigbee®, *Bluetooth*®5.2 Low Energy, IEEE 802.15.4g, TI 15.4-Stack (2.4 GHz). The CC2651P3 is based on an Arm® Cortex® M4 main processor and optimized for low-power wireless communication and advanced sensing in grid infrastructure, building automation, retail automation, personal electronics and medical applications.

The CC2651P3 has a software defined radio powered by an Arm® Cortex® M0, which allows support for multiple physical layers and RF standards. The device supports operation in the 2360 to 2500-MHz frequency band. The CC2651P3 has an efficient built-in PA that supports +10 dBm TX at 21 mA and +20 dBm TX at 101 mA (7x7 package). CC2651P3 has a receive sensitivity of -104 dBm for 125-kbps Bluetooth® Low Energy Coded PHY.

The CC2651P3 has a low sleep current of 0.8 µA with RTC and 32KB RAM retention.

Consistent with many customers' 10 to 15 years or longer life cycle requirements, TI has a product life cycle policy with a commitment to product longevity and continuity of supply.

The CC2651P3 device is part of the SimpleLink™ MCU platform, which consists of Wi-Fi®, *Bluetooth*® Low Energy, Thread, Zigbee, Wi-SUN®, Amazon Sidewalk, mioty, Sub-1 GHz MCUs, and host MCUs. CC2651P3 is part of a scalable portfolio with flash sizes from 32KB to 704KB with pin-to-pin compatible package options. The common SimpleLink™CC13xx and CC26xx Software Development Kit (SDK) and SysConfig system configuration tool supports migration between devices in the portfolio. A comprehensive number of software stacks, application examples and SimpleLink™ Academy training sessions are included in the SDK. For more information, visit wireless connectivity.

Device Information

PART NUMBER ⁽¹⁾	PACKAGE	BODY SIZE (NOM)
CC2651P31T0RGZR	VQFN (48)	7.00 mm × 7.00 mm
CC2651P31T0RKPR	VQFN (40)	5.00 mm × 5.00 mm

(1) For the most current part, package, and ordering information for all available devices, see the Package Option Addendum in Section 12, or see the TI website.

Product Folder Links: CC2651P3

¹ See RF Core for additional details on supported protocol standards, modulation formats, and data rates.

4 Functional Block Diagram

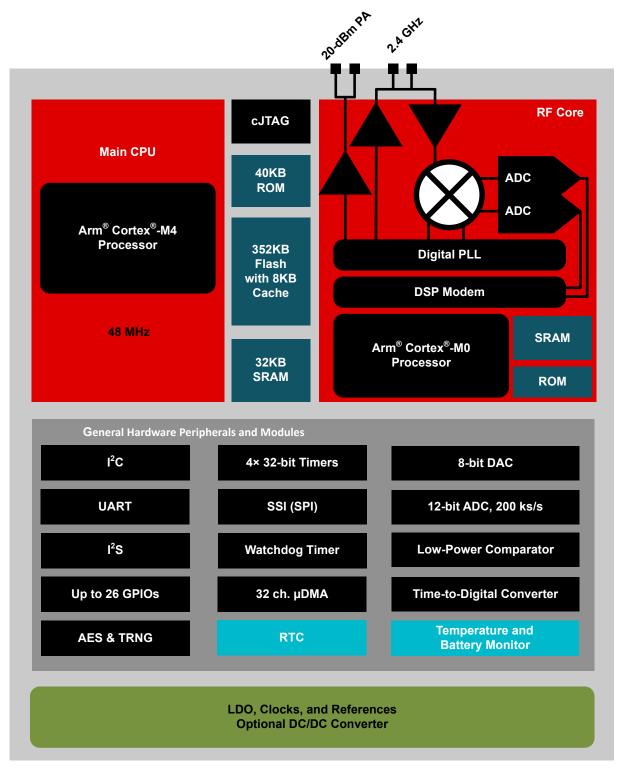


Figure 4-1. CC2651P3 Functional Block Diagram



Table of Contents

1 Features	1	8.15 Peripheral Characteristics	25
2 Applications	<mark>2</mark>	8.16 Typical Characteristics	31
3 Description	<mark>2</mark>	9 Detailed Description	
4 Functional Block Diagram	3	9.1 Overview	39
5 Revision History	4	9.2 System CPU	39
6 Device Comparison	<mark>5</mark>	9.3 Radio (RF Core)	40
7 Pin Configuration and Functions	6	9.4 Memory	41
7.1 Pin Diagram – RGZ Package (Top View)		9.5 Cryptography	42
7.2 Signal Descriptions – RGZ Package	<mark>7</mark>	9.6 Timers	43
7.3 Pin Diagram - RKP Package (Top View)	9	9.7 Serial Peripherals and I/O	44
7.4 Signal Descriptions – RKP Package	9	9.8 Battery and Temperature Monitor	44
7.5 Connections for Unused Pins and Modules	11	9.9 µDMA	44
8 Specifications	12	9.10 Debug	
8.1 Absolute Maximum Ratings	12	9.11 Power Management	45
8.2 ESD Ratings	12	9.12 Clock Systems	46
8.3 Recommended Operating Conditions	12	9.13 Network Processor	46
8.4 Power Supply and Modules	12	10 Application, Implementation, and Layout	47
8.5 Power Consumption - Power Modes	13	10.1 Reference Designs	
8.6 Power Consumption - Radio Modes	14	11 Device and Documentation Support	48
8.7 Nonvolatile (Flash) Memory Characteristics	14	11.1 Device Nomenclature	48
8.8 Thermal Resistance Characteristics	14	11.2 Tools and Software	49
8.9 RF Frequency Bands	15	11.3 Documentation Support	<mark>51</mark>
8.10 Bluetooth Low Energy - Receive (RX)	16	11.4 Support Resources	<mark>51</mark>
8.11 Bluetooth Low Energy - Transmit (TX)	19	11.5 Trademarks	<u>51</u>
8.12 Zigbee - IEEE 802.15.4-2006 2.4 GHz		11.6 Electrostatic Discharge Caution	52
(OQPSK DSSS1:8, 250 kbps) - RX	20	11.7 Glossary	52
8.13 Zigbee - IEEE 802.15.4-2006 2.4 GHz		12 Mechanical, Packaging, and Orderable	
(OQPSK DSSS1:8, 250 kbps) - TX	<mark>21</mark>	Information	<u>53</u>
8.14 Timing and Switching Characteristics	22		

5 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	NOTES
March 2022	*	Initial Release



6 Device Comparison

		RADIO SUPPORT												PA	CKA	GE SI	ZE	
Device	Sub-1 GHz Prop.	2.4GHz Prop.	Wireless M-Bus	mioty	Wi-SUN®	Sidewalk	Bluetooth® 5.2 LE	ZigBee	Thread	Multiprotocol	+20 dBm PA	FLASH (KB)	RAM + Cache (KB)	GPIO	4 X 4 mm VQFN (32)	5 X 5 mm VQFN (32)	5 X 5 mm VQFN (40)	7 X 7 mm VQFN (48)
CC1310	Х		Х	Х								32-128	16-20 + 8	10-30	Х	Х		Х
CC1311R3	Х		Х	Х								352	32 + 8	22-30			Х	Х
CC1311P3	Х		Х	Х							Х	352	32 + 8	26				Х
CC1312R	Х		Х	Х	Х							352	80 + 8	30				Х
CC1312R7	Х		Х	Х	Х	Х				Х		704	144 + 8	30				Х
CC1352R	Х	Х	Х	Х	Х		Х	Х	Х	Х		352	80 + 8	28				Х
CC1352P	Х	Х	Х	Х	Х		Х	Х	Х	Х	Х	352	80 + 8	26				Х
CC1352P7	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х	704	144 + 8	26				Х
CC2640R2F							Х					128	20 + 8	10-31	Х	Х		Х
CC2642R							Х					352	80 + 8	31				Х
CC2642R-Q1							Х					352	80 + 8	31				Х
CC2651R3		Х					Х	Х				352	32 + 8	23-31			Х	Х
CC2651P3		Х					Х	Х			Х	352	32 + 8	22-26			Х	Х
CC2652R		Х					Х	Х	Х	Х		352	80 + 8	31				Х
CC2652RB		Х					Х	Х	Х	Х		352	80 + 8	31				Х
CC2652R7		Х					Х	Х	Х	Х		704	144 + 8	31				Х
CC2652P		Х					Х	Х	Х	Х	Х	352	80 + 8	26				Х
CC2652P7		Х					Х	Х	Х	Х	Х	704	144 + 8	26				Х



7 Pin Configuration and Functions

7.1 Pin Diagram – RGZ Package (Top View)

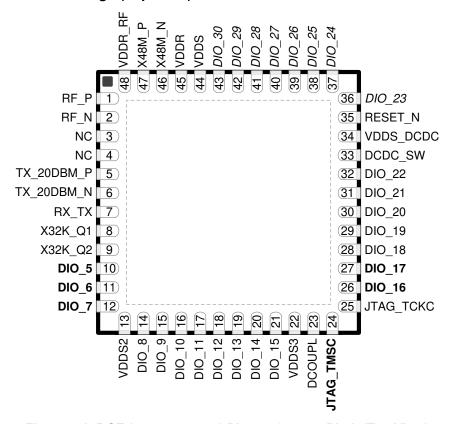


Figure 7-1. RGZ (7-mm × 7-mm) Pinout, 0.5-mm Pitch (Top View)

The following I/O pins marked in Figure 7-1 in **bold** have high-drive capabilities:

- Pin 10, DIO_5
- Pin 11, DIO 6
- Pin 12, DIO_7
- Pin 24, JTAG TMSC
- Pin 26, DIO 16
- Pin 27, DIO_17

The following I/O pins marked in Figure 7-1 in *italics* have analog capabilities:

- Pin 36, DIO_23
- Pin 37, DIO 24
- Pin 38, DIO 25
- Pin 39, DIO_26
- Pin 40, DIO_27
- Pin 41, DIO_28Pin 42, DIO_29
- Pin 43, DIO 30



7.2 Signal Descriptions – RGZ Package

Table 7-1. Signal Descriptions – RGZ Package

Table 7-1. Signal Descriptions – RGZ Package								
NAME	NO.	I/O	TYPE	DESCRIPTION				
DCDC_SW	33	_	Power	Output from internal DC/DC converter ⁽¹⁾				
DCOUPL	23	_	Power	For decoupling of internal 1.27 V regulated digital-supply (2)				
DIO_5	10	I/O	Digital	GPIO, high-drive capability				
DIO_6	11	I/O	Digital	GPIO, high-drive capability				
DIO_7	12	I/O	Digital	GPIO, high-drive capability				
DIO_8	14	I/O	Digital	GPIO				
DIO_9	15	I/O	Digital	GPIO				
DIO_10	16	I/O	Digital	GPIO				
DIO_11	17	I/O	Digital	GPIO				
DIO_12	18	I/O	Digital	GPIO				
DIO_13	19	I/O	Digital	GPIO				
DIO_14	20	I/O	Digital	GPIO				
DIO_15	21	I/O	Digital	GPIO				
DIO_16	26	I/O	Digital	GPIO, JTAG_TDO, high-drive capability				
DIO_17	27	I/O	Digital	GPIO, JTAG_TDI, high-drive capability				
DIO_18	28	I/O	Digital	GPIO				
DIO_19	29	I/O	Digital	GPIO				
DIO_20	30	I/O	Digital	GPIO				
DIO_21	31	I/O	Digital	GPIO				
DIO_22	32	I/O	Digital	GPIO				
DIO_23	36	I/O	Digital or Analog	GPIO, analog capability				
DIO_24	37	I/O	Digital or Analog	GPIO, analog capability				
DIO_25	38	I/O	Digital or Analog	GPIO, analog capability				
DIO_26	39	I/O	Digital or Analog	GPIO, analog capability				
DIO_27	40	I/O	Digital or Analog	GPIO, analog capability				
DIO_28	41	I/O	Digital or Analog	GPIO, analog capability				
DIO_29	42	I/O	Digital or Analog	GPIO, analog capability				
DIO_30	43	I/O	Digital or Analog	GPIO, analog capability				
EGP	_	_	GND	Ground – exposed ground pad ⁽³⁾				
JTAG_TMSC	24	I/O	Digital	JTAG TMSC, high-drive capability				
JTAG_TCKC	25	I	Digital	JTAG TCKC				
RESET_N	35	I	Digital	Reset, active low. No internal pullup resistor				
RF_P	1	_	RF	Positive RF input signal to LNA during RX Positive RF output signal from PA during TX				
RF_N	2	_	RF	Negative RF input signal to LNA during RX Negative RF output signal from PA during TX				
RX_TX	7	_	RF	Optional bias pin for the RF LNA				
TX_20DBM_P	5	-	RF	Positive high-power TX signal				
TX_20DBM_N	6	-	RF	Negative high-power TX signal				
VDDR	45	_	Power	Internal supply, must be powered from the internal DC/DC converter or the internal LDO ⁽²⁾ (4) (6)				
VDDR_RF	48	_	Power	Internal supply, must be powered from the internal DC/DC converter or the internal LDO ⁽²⁾ (5) (6)				
VDDS	44		Power	1.8-V to 3.8-V main chip supply ⁽¹⁾				



Table 7-1. Signal Descriptions – RGZ Package (continued)

PIN		I/O	TYPE	DESCRIPTION
NAME	NO.	IVO TIPE		DESCRIPTION
VDDS2	13	_	Power	1.8-V to 3.8-V DIO supply ⁽¹⁾
VDDS3	22	_	Power	1.8-V to 3.8-V DIO supply ⁽¹⁾
VDDS_DCDC	34	_	Power	1.8-V to 3.8-V DC/DC converter supply
X48M_N	46	_	Analog	48-MHz crystal oscillator pin 1
X48M_P	47	_	Analog	48-MHz crystal oscillator pin 2
X32K_Q1	8	_	Analog	32-kHz crystal oscillator pin 1
X32K_Q2	9	_	Analog	32-kHz crystal oscillator pin 2

- (1) For more details, see the device technical reference manual listed in Section 11.3.
- (2) Do not supply external circuitry from this pin.
- (3) EGP is the only ground connection for the device. Good electrical connection to device ground on printed circuit board (PCB) is imperative for proper device operation.
- (4) If internal DC/DC converter is not used, this pin is supplied internally from the main LDO.
- (5) If internal DC/DC converter is not used, this pin must be connected to VDDR for supply from the main LDO.
- (6) Output from internal DC/DC and LDO is trimmed to 1.68 V.



7.3 Pin Diagram – RKP Package (Top View)

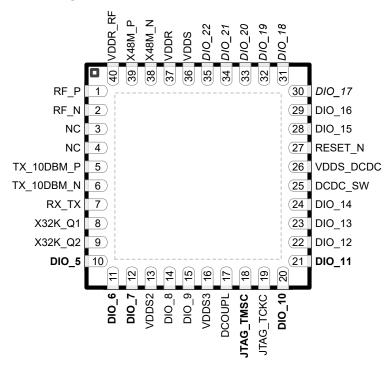


Figure 7-2. RKP (5-mm × 5-mm) Pinout, 0.4-mm Pitch (Top View)

The following I/O pins marked in Figure 7-2 in **bold** have high-drive capabilities:

- Pin 10, DIO_5
- Pin 11, DIO 6
- Pin 12, DIO_7
- Pin 18, JTAG TMSC
- Pin 20, DIO 10
- Pin 21, DIO_11

The following I/O pins marked in Figure 7-2 in *italics* have analog capabilities:

- Pin 28, DIO_15
- Pin 29, DIO_16
- Pin 30, DIO 17
- Pin 31, DIO_18
- Pin 32, DIO 19
- Pin 33, DIO_20
- Pin 34, DIO_21
- Pin 35, DIO_22

7.4 Signal Descriptions - RKP Package

Table 7-2. Signal Descriptions - RKP Package

			•	•	
PIN		I/O	TYPE	DESCRIPTION	
NAME	NO.	1/0	1175	DESCRIPTION	
DCDC_SW	25	_	Power	Output from internal DC/DC converter ⁽¹⁾	
DCOUPL	17	_	Power	For decoupling of internal 1.27 V regulated digital-supply (2)	
DIO_5	10	I/O	Digital	GPIO, high-drive capability	
DIO_6	11	I/O	Digital	GPIO, high-drive capability	
DIO_7	12	I/O	Digital	GPIO, high-drive capability	



Table 7-2. Signal Descriptions – RKP Package (continued)

NAME	PIN	PIN Package (continued)								
DIO_8		NO	I/O	TYPE	DESCRIPTION					
DIO_9			1/0	Digital	GPIO					
DO_10				•						
DIO_11										
DIO_12										
DIO_13				_						
DIO_14										
DIO_15										
DIO_16				_						
DIO_17 30					, , , ,					
DIO_18										
DIO_19				_						
DIO_20 33										
DIO_21 34 I/O										
DIO_22 35 I/O Digital GPIO, analog capability EGP — — GND Ground – exposed ground pad(3) JTAG_TSMC 18 I/O Digital JTAG_TMSC, high-drive capability JTAG_TCKC 19 I Digital JTAG_TCKC RESET_N 27 I Digital Reset, active low. No internal pullup resistor RF_P 1 — RF Positive RF input signal to LNA during RX Positive RF output signal from PA during TX RF_N 2 — RF Negative RF input signal to LNA during RX Negative RF output signal from PA during TX RX_TX 7 — RF Optional bias pin for the RF LNA RX_2DBM_P 5 — RF Positive high-power TX signal VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (6) (6) VDDS 36 — Power 1.8-V to 3.8-V main chip su				_						
EGP — — GND Ground – exposed ground pad(3) JTAG_TSMC 18 I/O Digital JTAG_TMSC, high-drive capability JTAG_TCKC 19 I Digital JTAG_TCKC RESET_N 27 I Digital Reset, active low. No internal pullup resistor RF_P 1 — RF Positive RF input signal to LNA during RX Positive RF output signal from PA during TX RF_N 2 — RF Negative RF output signal from PA during TX RX_TX 7 — RF Optional bias pin for the RF LNA TX_20DBM_P 5 — RF Positive high-power TX signal VDDR 37 — RF Negative high-power TX signal VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (6) (6) VDDS 36 — Power 1.8-V to 3.8-V main chip supply(1)				<u> </u>	, , , ,					
JTAG_TSMC 18 I/O Digital JTAG_TMSC, high-drive capability JTAG_TCKC 19 I Digital JTAG_TCKC RESET_N 27 I Digital Reset, active low. No internal pullup resistor RF_P 1 — RF Positive RF input signal to LNA during RX Positive RF output signal from PA during TX RF_N 2 — RF Negative RF input signal to LNA during RX Negative RF output signal from PA during TX RX_TX 7 — RF Optional bias pin for the RF LNA TX_20DBM_P 5 — RF Positive high-power TX signal TX_20DBM_N 6 — RF Negative high-power TX signal VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (5) (6) VDDS 36 — Power 1.8-V to 3.8-V main chip supply(1) VDDS 16 — Power 1.8-V to 3.8-V D		35	1/0							
JTAG_TCKC 19 I Digital JTAG TCKC RESET_N 27 I Digital Reset, active low. No internal pullup resistor RF_P 1 — RF Positive RF input signal to LNA during RX Positive RF output signal from PA during TX RF_N 2 — RF Negative RF output signal from PA during RX Negative RF output signal from PA during TX RX_TX 7 — RF Optional bias pin for the RF LNA TX_20DBM_P 5 — RF Positive high-power TX signal TX_20DBM_N 6 — RF Negative high-power TX signal VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (5) (6) VDDS 36 — Power 1.8-V to 3.8-V bio supply(1) VDDS2 13 — Power 1.8-V to 3.8-V DIO supply(1) VDDS3 16 — Power 1.8-V to 3.8-V DIO supply(1) <td></td> <td>_</td> <td>_</td> <td></td> <td></td>		_	_							
RESET_N 27 I Digital Reset, active low. No internal pullup resistor RF_P 1 — RF Positive RF input signal to LNA during RX Positive RF output signal from PA during TX RF_N 2 — RF Negative RF input signal to LNA during RX Negative RF output signal from PA during TX RX_TX 7 — RF Optional bias pin for the RF LNA TX_20DBM_P 5 — RF Positive high-power TX signal TX_20DBM_N 6 — RF Negative high-power TX signal VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (5) (6) VDDS 36 — Power 1.8-V to 3.8-V main chip supply(1) VDDS 36 — Power 1.8-V to 3.8-V DIO supply(1) VDDS3 16 — Power 1.8-V to 3.8-V DIO supply(1) VDDS_DCDC 26 — Power 1.8-V to 3.			I/O	_						
RF_P 1 — RF Positive RF input signal to LNA during RX Positive RF output signal from PA during TX RF_N 2 — RF Negative RF input signal from PA during TX RX_TX 7 — RF Optional bias pin for the RF LNA TX_20DBM_P 5 — RF Positive high-power TX signal TX_20DBM_N 6 — RF Negative high-power TX signal VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power I.8-V to 3.8-V DIO supply(1) VDDS3 16 — Power 1.8-V to 3.8-V DIO supply(1) VDDS_DCDC 26 — Power 1.8-V to 3.8-V DIO converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 32-kHz crystal oscillator pin 1 X48M_P 39 Analog 32-kHz crystal oscillator pin 1		19	I	Digital						
RF_N 2 — RF Negative RF output signal from PA during TX RF_N 2 — RF Negative RF input signal to LNA during RX Negative RF output signal from PA during TX RX_TX 7 — RF Optional bias pin for the RF LNA TX_20DBM_P 5 — RF Positive high-power TX signal TX_20DBM_N 6 — RF Negative high-power TX signal VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power I.8-V to 3.8-V main chip supply(1) VDDS 36 — Power I.8-V to 3.8-V DIO supply(1) VDDS2 13 — Power I.8-V to 3.8-V DIO supply(1) VDDS3 16 — Power I.8-V to 3.8-V DIO supply(1) VDDS_DCDC 26 — Power I.8-V to 3.8-V DC/DC converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 32-kHz crystal oscillator pin 1	RESET_N	27	I	Digital	Reset, active low. No internal pullup resistor					
RF_N 2 RF Negative RF output signal from PA during TX RX_TX 7 — RF Optional bias pin for the RF LNA TX_20DBM_P 5 — RF Positive high-power TX signal TX_20DBM_N 6 — RF Negative high-power TX signal VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (5) (6) VDDS 36 — Power 1.8-V to 3.8-V main chip supply(1) VDDS2 13 — Power 1.8-V to 3.8-V DIO supply(1) VDDS3 16 — Power 1.8-V to 3.8-V DIO supply(1) VDDS_DCDC 26 — Power 1.8-V to 3.8-V DC/DC converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 32-kHz crystal oscillator pin 1	RF_P	1	_	RF						
TX_20DBM_P 5 — RF Positive high-power TX signal TX_20DBM_N 6 — RF Negative high-power TX signal VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (5) (6) VDDS 36 — Power 1.8-V to 3.8-V main chip supply(1) VDDS2 13 — Power 1.8-V to 3.8-V DIO supply(1) VDDS3 16 — Power 1.8-V to 3.8-V DIO supply(1) VDDS_DCDC 26 — Power 1.8-V to 3.8-V DC/DC converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 32-kHz crystal oscillator pin 1	RF_N	2	_	RF						
TX_20DBM_N 6 — RF Negative high-power TX signal VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (5) (6) VDDS 36 — Power 1.8-V to 3.8-V main chip supply(1) VDDS2 13 — Power 1.8-V to 3.8-V DIO supply(1) VDDS3 16 — Power 1.8-V to 3.8-V DIO supply(1) VDDS_DCDC 26 — Power 1.8-V to 3.8-V DIO supply(1) VDDS_DCDC 26 — Power 1.8-V to 3.8-V DIO converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 32-kHz crystal oscillator pin 1	RX_TX	7	_	RF	Optional bias pin for the RF LNA					
VDDR 37 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (4) (6) VDDR_RF 40 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (5) (6) VDDS 36 — Power 1.8-V to 3.8-V main chip supply(1) VDDS2 13 — Power 1.8-V to 3.8-V DIO supply(1) VDDS3 16 — Power 1.8-V to 3.8-V DIO supply(1) VDDS_DCDC 26 — Power 1.8-V to 3.8-V DC/DC converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 32-kHz crystal oscillator pin 2	TX_20DBM_P	5	_	RF	Positive high-power TX signal					
VDDR_RF 40 — Power Internal supply, must be powered from the internal DC/DC converter or the internal LDO(2) (5) (6) VDDS 36 — Power 1.8-V to 3.8-V main chip supply(1) VDDS2 13 — Power 1.8-V to 3.8-V DIO supply(1) VDDS3 16 — Power 1.8-V to 3.8-V DIO supply(1) VDDS_DCDC 26 — Power 1.8-V to 3.8-V DC/DC converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 48-MHz crystal oscillator pin 2 X32K_Q1 8 — Analog 32-kHz crystal oscillator pin 1	TX_20DBM_N	6	_	RF	Negative high-power TX signal					
VDDR_RF 40 — Power converter or the internal LDO(2) (5) (6) VDDS 36 — Power 1.8-V to 3.8-V main chip supply(1) VDDS2 13 — Power 1.8-V to 3.8-V DIO supply(1) VDDS3 16 — Power 1.8-V to 3.8-V DIO supply(1) VDDS_DCDC 26 — Power 1.8-V to 3.8-V DC/DC converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 48-MHz crystal oscillator pin 2 X32K_Q1 8 — Analog 32-kHz crystal oscillator pin 1	VDDR	37	_	Power						
VDDS2 13 — Power 1.8-V to 3.8-V DIO supply ⁽¹⁾ VDDS3 16 — Power 1.8-V to 3.8-V DIO supply ⁽¹⁾ VDDS_DCDC 26 — Power 1.8-V to 3.8-V DC/DC converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 48-MHz crystal oscillator pin 2 X32K_Q1 8 — Analog 32-kHz crystal oscillator pin 1	VDDR_RF	40	_	Power						
VDDS3 16 — Power 1.8-V to 3.8-V DIO supply ⁽¹⁾ VDDS_DCDC 26 — Power 1.8-V to 3.8-V DC/DC converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 48-MHz crystal oscillator pin 2 X32K_Q1 8 — Analog 32-kHz crystal oscillator pin 1	VDDS	36	_	Power	1.8-V to 3.8-V main chip supply ⁽¹⁾					
VDDS_DCDC 26 — Power 1.8-V to 3.8-V DC/DC converter supply X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 48-MHz crystal oscillator pin 2 X32K_Q1 8 — Analog 32-kHz crystal oscillator pin 1	VDDS2	13	_	Power	1.8-V to 3.8-V DIO supply ⁽¹⁾					
X48M_N 38 — Analog 48-MHz crystal oscillator pin 1 X48M_P 39 — Analog 48-MHz crystal oscillator pin 2 X32K_Q1 8 — Analog 32-kHz crystal oscillator pin 1	VDDS3	16	_	Power	1.8-V to 3.8-V DIO supply ⁽¹⁾					
X48M_P 39 — Analog 48-MHz crystal oscillator pin 2 X32K_Q1 8 — Analog 32-kHz crystal oscillator pin 1	VDDS_DCDC	26	_	Power	1.8-V to 3.8-V DC/DC converter supply					
X48M_P 39 — Analog 48-MHz crystal oscillator pin 2 X32K_Q1 8 — Analog 32-kHz crystal oscillator pin 1	X48M_N	38	_	Analog	48-MHz crystal oscillator pin 1					
X32K_Q1 8 — Analog 32-kHz crystal oscillator pin 1		39	_	_	48-MHz crystal oscillator pin 2					
	X32K_Q1	8	_	Analog	32-kHz crystal oscillator pin 1					
		9	_	Analog						

- (1) For more details, see the device technical reference manual listed in Section 11.3.
- (2) Do not supply external circuitry from this pin.
- (3) EGP is the only ground connection for the device. Good electrical connection to device ground on printed circuit board (PCB) is imperative for proper device operation.
- (4) If internal DC/DC converter is not used, this pin is supplied internally from the main LDO.
- (5) If internal DC/DC converter is not used, this pin must be connected to VDDR for supply from the main LDO.
- (6) Output from internal DC/DC and LDO is trimmed to 1.68 V.



7.5 Connections for Unused Pins and Modules

Table 7-3. Connections for Unused Pins - RGZ Package

rance is a common of control in the state of											
FUNCTION	SIGNAL NAME	PIN NUMBER	ACCEPTABLE PRACTICE(1)	PREFERRED PRACTICE ⁽¹⁾							
GPIO	DIO_n	10–12 14–21 26–32 36–43	NC or GND	NC							
32.768-kHz crystal	X32K_Q1	8	NC or GND	NC							
32.700-KHZ CIYSIAI	X32K_Q2	9	- NC OF GND	INC							
No Connects	NC	3–4	NC	NC							
DC/DC converter ⁽²⁾	DCDC_SW	33	NC	NC							
DC/DC converter(2)	VDDS_DCDC	34	VDDS	VDDS							

⁽¹⁾ NC = No connect

Table 7-4. Connection for Unused Pins and Modules – RKP Package

FUNCTION	SIGNAL NAME	PIN NUMBER	ACCEPTABLE PRACTICE	PREFERRED PRACTICE
GPIO	DIO_n	10-12 14-15 20-24 28-35	NC or GND	NC
32.768-kHz crystal	X32K_Q1	3	NC or GND	NC
32.700-KHZ CI YSIAI	X32K_Q2	4	INC OF GIND	NC
No Connects	NC	3–4	NC	NC
DC/DC converter	DCDC_SW	25	NC	NC
DC/DC converter	VDDS_DCDC	26	VDDS	VDDS

⁽²⁾ When the DC/DC converter is not used, the inductor between DCDC_SW and VDDR can be removed. VDDR and VDDR_RF must still be connected and the 22 uF DCDC capacitor must be kept on the VDDR net.



8 Specifications

8.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1) (2)

			MIN	MAX	UNIT
VDDS ⁽³⁾ (6)	Supply voltage		-0.3	4.1	V
	Voltage on any digital pin	(4) (5)	-0.3	VDDS + 0.3, max 4.1	V
	Voltage on crystal oscilla	tor pins, X32K_Q1, X32K_Q2, X48M_N and X48M_P	-0.3	VDDR + 0.3, max 2.25	V
	Voltage on ADC input	Voltage scaling enabled	-0.3	VDDS	
V _{in}		Voltage scaling disabled, internal reference	-0.3	1.49	V
		Voltage scaling disabled, VDDS as reference	-0.3	VDDS / 2.9	
	Input level, RF pins (RF_	P and RF_N)		5	dBm
T _{stg}	Storage temperature		-40	150	°C

- (1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime
- (2) All voltage values are with respect to ground, unless otherwise noted.
- (3) VDDS_DCDC, VDDS2 and VDDS3 must be at the same potential as VDDS.
- (4) Including analog capable DIOs.
- (5) Injection current is not supported on any GPIO pin
- (6) Connect VDDR to the external PA bias voltage for +10dBm and VDDS to the external PA bias voltage for +14dBm to +20dBm

8.2 ESD Ratings

				VALUE	UNIT
V	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS001 ⁽¹⁾	All pins	±2000	V
V _{ESD}	Liectiostatic discharge	Charged device model (CDM), per JESD22-C101 ⁽²⁾	All pins	±500	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

8.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

	MIN	MAX	UNIT
Operating ambient temperature ^{(1) (2)}	-40	105	°C
Operating junction temperature ^{(1) (2)}	-40	115	°C
Operating supply voltage (VDDS)	1.8	3.8	V
Rising supply voltage slew rate	0	100	mV/μs
Falling supply voltage slew rate ⁽³⁾	0	20	mV/μs

- (1) Operation at or near maximum operating temperature for extended durations will result in lifetime reduction.
- (2) For thermal resistance characteristics refer to Section 8.8.
- (3) For small coin-cell batteries, with high worst-case end-of-life equivalent source resistance, a 22-μF VDDS input capacitor must be used to ensure compliance with this slew rate.

8.4 Power Supply and Modules

over operating free-air temperature range (unless otherwise noted)

PARAMETER		MIN	TYP MA	X UNIT
VDDS Power-on-Reset (POR) threshold		1.1 -	1.55	V
VDDS Brown-out Detector (BOD)	Rising threshold		1.77	V
VDDS Brown-out Detector (BOD), before initial boot (1)	Rising threshold		1.70	V
VDDS Brown-out Detector (BOD)	Falling threshold		1.75	V

(1) Brown-out Detector is trimmed at initial boot, value is kept until device is reset by a POR reset or the RESET_N pin



8.5 Power Consumption - Power Modes

When measured on the CC26x1-P3EM-XD24-PA24 reference design with T_c = 25 °C, V_{DDS} = 3.0 V with DC/DC enabled unless otherwise noted.

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Core Curr	ent Consumption					
	Reset and Shutdown	Reset. RESET_N pin asserted or VDDS below power-on-reset threshold		150		nA
	Shuldown	Shutdown. No clocks running, no retention		100		
	Standby without cache	RTC running, CPU, 32KB RAM and (partial) register retention. RCOSC_LF		0.8		μA
	retention	RTC running, CPU, 32KB RAM and (partial) register retention XOSC_LF		0.9		μA
I _{core}	Standby	RTC running, CPU, 32KB RAM and (partial) register retention. RCOSC_LF		2.4		μA
	with cache retention	RTC running, CPU, 32KB RAM and (partial) register retention. XOSC_LF		2.6		μA
	Idle	Supply Systems and RAM powered RCOSC_HF		650		μA
Active	Active	MCU running CoreMark at 48 MHz RCOSC_HF		2.91		mA
Periphera	I Current Consumption				Į.	
	Peripheral power domain	Delta current with domain enabled		56.0		
	Serial power domain	Delta current with domain enabled		5.0		
	RF Core	Delta current with power domain enabled, clock enabled, RF core idle		144		
	μDMA	Delta current with clock enabled, module is idle		68.6		
I _{peri}	Timers	Delta current with clock enabled, module is idle ⁽¹⁾		102		μA
·pen	I2C	Delta current with clock enabled, module is idle		12.1		μ/ ι
	128	Delta current with clock enabled, module is idle		30.8		
	SSI	Delta current with clock enabled, module is idle		71.7		
	UART	Delta current with clock enabled, module is idle		147		
	CRYPTO (AES)	Delta current with clock enabled, module is idle		28.1		
	TRNG	Delta current with clock enabled, module is idle		27.1		

(1) Only one GPTimer running



8.6 Power Consumption - Radio Modes

When measured on the CC26x1-P3EM-XD24-PA24 reference design with T_c = 25 °C, V_{DDS} = 3.0 V with DC/DC enabled unless otherwise noted.

High-power PA connected to V_{DDS} unless otherwise noted.

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Radio receive current	2440 MHz		6.4		mA
Radio transmit current	0 dBm output power setting 2440 MHz		7.1		mA
2.4 GHz PA (Bluetooth Low Energy)	+5 dBm output power setting 2440 MHz		9.5		mA
Radio transmit current High-power PA	+20 dBm output power setting ⁽¹⁾ 2440 MHz. VDDS = 3.3 V		101		mA
Radio transmit current High-power PA, 10 dBm configuration ⁽²⁾	+10 dBm output power setting 2440 MHz VDDR = 1.67 V		22		mA

- (1) +20 dBm is only available on the RGZ (7x7) package
- (2) Measured on evaluation board as described in https://www.ti.com/lit/pdf/swra636.

8.7 Nonvolatile (Flash) Memory Characteristics

Over operating free-air temperature range and V_{DDS} = 3.0 V (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Flash sector size			8		KB
Supported flash erase cycles before failure, full bank ⁽¹⁾ (5)		30			k Cycles
Supported flash erase cycles before failure, single sector ⁽²⁾		60			k Cycles
Maximum number of write operations per row before sector erase ⁽³⁾				83	Write Operations
Flash retention	105 °C	11.4			Years
Flash sector erase current	Average delta current		9.7		mA
Flash sector erase time ⁽⁴⁾	Zero cycles		10		ms
Flash sector erase time (7)	30k cycles			4000	ms
Flash write current	Average delta current, 4 bytes at a time		5.3		mA
Flash write time ⁽⁴⁾	4 bytes at a time		21.6		μs

- (1) A full bank erase is counted as a single erase cycle on each sector.
- (2) Up to 4 customer-designated sectors can be individually erased an additional 30k times beyond the baseline bank limitation of 30k cycles
- (3) Each wordline is 2048 bits (or 256 bytes) wide. This limitation corresponds to sequential memory writes of 4 (3.1) bytes minimum per write over a whole wordline. If additional writes to the same wordline are required, a sector erase is required once the maximum number of write operations per row is reached.
- (4) This number is dependent on Flash aging and increases over time and erase cycles
- (5) Aborting flash during erase or program modes is not a safe operation.

8.8 Thermal Resistance Characteristics

		PAC		
	THERMAL METRIC(1)	RGZ (VQFN)	RKP (VQFN)	UNIT
		48 PINS	40 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	25.0	30.9	°C/W ⁽²⁾
R _{0JC(top)}	Junction-to-case (top) thermal resistance	14.5	20.2	°C/W ⁽²⁾
$R_{\theta JB}$	Junction-to-board thermal resistance	8.7	10.3	°C/W ⁽²⁾
ΨЈТ	Junction-to-top characterization parameter	0.2	0.2	°C/W ⁽²⁾
ΨЈВ	Junction-to-board characterization parameter	8.6	10.3	°C/W ⁽²⁾
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	2.1	2.1	°C/W ⁽²⁾

- (1) For more information about traditional and new thermal metrics, see Semiconductor and IC Package Thermal Metrics.
- (2) °C/W = degrees Celsius per watt.







8.9 RF Frequency Bands

Over operating free-air temperature range (unless otherwise noted).

PARAMETER	MIN	TYP	MAX	UNIT
Frequency bands	2360		2500	MHz



8.10 Bluetooth Low Energy - Receive (RX)

Measured on the CC26x1-P3EM-7XD24-PA24 reference design with T_c = 25 °C, V_{DDS} = 3.0 V, f_{RF} = 2440 MHz with DC/DC enabled and high power PA connected to V_{DDS} unless otherwise noted.

All measurements are performed at the antenna input with a combined RX and TX path, except for high power PA which is measured at a dedicated antenna connection. All measurements are performed conducted.

PARAMETER	TEST CONDITIONS	MIN TYP I	MAX UNIT
125 kbps (LE Coded)			
Receiver sensitivity	Differential mode. BER = 10 ⁻³	-104	dBm
Receiver sensitivity	Single ended mode. Measured on CC26x1- P3EM-5XS24, at the SMA connector, BER = 10 ⁻³	-104	dBm
Receiver saturation	Differential mode. BER = 10 ⁻³	>5	dBm
Frequency error tolerance	Difference between the incoming carrier frequency and the internally generated carrier frequency	> (-300 / 300)	kHz
Data rate error tolerance	Difference between incoming data rate and the internally generated data rate (37-byte packets)	> (-320 / 240)	ppm
Data rate error tolerance	Difference between incoming data rate and the internally generated data rate (255-byte packets)	> (–125 / 125)	ppm
Co-channel rejection ⁽¹⁾	Wanted signal at –79 dBm, modulated interferer in channel, BER = 10 ⁻³	-1.5	dB
Selectivity, ±1 MHz ⁽¹⁾	Wanted signal at -79 dBm, modulated interferer at ± 1 MHz, BER = 10^{-3}	8 / 4.5 ⁽²⁾	dB
Selectivity, ±2 MHz ⁽¹⁾	Wanted signal at -79 dBm, modulated interferer at ± 2 MHz, BER = 10^{-3}	44 / 39 ⁽²⁾	dB
Selectivity, ±3 MHz ⁽¹⁾	Wanted signal at -79 dBm, modulated interferer at ± 3 MHz, BER = 10^{-3}	46 / 44 ⁽²⁾	dB
Selectivity, ±4 MHz ⁽¹⁾	Wanted signal at -79 dBm, modulated interferer at ± 4 MHz, BER = 10^{-3}	44 / 46 ⁽²⁾	dB
Selectivity, ±6 MHz ⁽¹⁾	Wanted signal at -79 dBm, modulated interferer at ≥ ± 6 MHz, BER = 10^{-3}	48 / 44 ⁽²⁾	dB
Selectivity, ±7 MHz	Wanted signal at -79 dBm, modulated interferer at $\geq \pm 7$ MHz, BER = 10^{-3}	51 / 45 ⁽²⁾	dB
Selectivity, Image frequency ⁽¹⁾	Wanted signal at -79 dBm, modulated interferer at image frequency, BER = 10^{-3}	39	dB
Selectivity, Image frequency ±1 MHz ⁽¹⁾	Note that Image frequency + 1 MHz is the Co- channel -1 MHz. Wanted signal at -79 dBm, modulated interferer at ±1 MHz from image frequency, BER = 10 ⁻³	4.5 / 44 (2)	dB
500 kbps (LE Coded)			
Receiver sensitivity	Differential mode. BER = 10 ⁻³	-100	dBm
Receiver sensitivity	Single ended mode. Measured on CC26x1- P3EM-5XS24, at the SMA connector, BER = 10 ⁻³	-100	dBm
Receiver saturation	Differential mode. BER = 10 ⁻³	> 5	dBm
Frequency error tolerance	Difference between the incoming carrier frequency and the internally generated carrier frequency	> (-300 / 300)	kHz
Data rate error tolerance	Difference between incoming data rate and the internally generated data rate (37-byte packets)	> (-450 / 450)	ppm
Data rate error tolerance	Difference between incoming data rate and the internally generated data rate (255-byte packets)	> (–175 / 175)	ppm
Co-channel rejection ⁽¹⁾	Wanted signal at –72 dBm, modulated interferer in channel, BER = 10 ⁻³	-3.5	dB
Selectivity, ±1 MHz ⁽¹⁾	Wanted signal at -72 dBm, modulated interferer at ± 1 MHz, BER = 10^{-3}	8 / 4 ⁽²⁾	dB
Selectivity, ±2 MHz ⁽¹⁾	Wanted signal at -72 dBm, modulated interferer at ± 2 MHz, BER = 10^{-3}	44 / 37 ⁽²⁾	dB
Selectivity, ±3 MHz ⁽¹⁾	Wanted signal at -72 dBm, modulated interferer at ± 3 MHz, BER = 10^{-3}	46 / 46 ⁽²⁾	dB
Selectivity, ±4 MHz ⁽¹⁾	Wanted signal at -72 dBm, modulated interferer at ± 4 MHz, BER = 10^{-3}	45 / 47 ⁽²⁾	dB
Selectivity, ±6 MHz ⁽¹⁾	Wanted signal at –72 dBm, modulated interferer at ≥ ±6 MHz. BER = 10 ⁻³	46 / 45 ⁽²⁾	dB

Submit Document Feedback

Copyright © 2022 Texas Instruments Incorporated



8.10 Bluetooth Low Energy - Receive (RX) (continued)

Measured on the CC26x1-P3EM-7XD24-PA24 reference design with T_c = 25 °C, V_{DDS} = 3.0 V, f_{RF} = 2440 MHz with DC/DC enabled and high power PA connected to V_{DDS} unless otherwise noted. All measurements are performed at the antenna input with a combined RX and TX path, except for high power PA which is

measured at a dedicated antenna connection. All measurements are performed conducted

PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
Selectivity, ±7 MHz	Wanted signal at –72 dBm, modulated interferer at ≥ ±7 MHz, BER = 10 ⁻³	49 / 45 ⁽²⁾		dB
Selectivity, Image frequency ⁽¹⁾	Wanted signal at –72 dBm, modulated interferer at image frequency, BER = 10 ⁻³	37		dB
Selectivity, Image frequency ±1 MHz ⁽¹⁾	Note that Image frequency + 1 MHz is the Co- channel -1 MHz. Wanted signal at -72 dBm, modulated interferer at ±1 MHz from image frequency, BER = 10 ⁻³	4 / 46 ⁽²⁾		dB
1 Mbps (LE 1M)				
Receiver sensitivity	Differential mode. BER = 10 ⁻³	-97		dBm
Receiver sensitivity	Single ended mode. Measured on CC26x1- P3EM-5XS24, at the SMA connector, BER = 10 ⁻³	-97		dBm
Receiver saturation	Differential mode. BER = 10 ⁻³	> 5		dBm
Frequency error tolerance	Difference between the incoming carrier frequency and the internally generated carrier frequency	> (-350 / 350)		kHz
Data rate error tolerance	Difference between incoming data rate and the internally generated data rate (37-byte packets)	> (-750 / 750)		ppm
Co-channel rejection ⁽¹⁾	Wanted signal at –67 dBm, modulated interferer in channel, BER = 10 ⁻³	-6		dB
Selectivity, ±1 MHz ⁽¹⁾	Wanted signal at –67 dBm, modulated interferer at ±1 MHz, BER = 10 ⁻³	7 / 4 ⁽²⁾		dB
Selectivity, ±2 MHz ⁽¹⁾	Wanted signal at –67 dBm, modulated interferer at ±2 MHz,BER = 10 ⁻³	40 / 33 ⁽²⁾		dB
Selectivity, ±3 MHz ⁽¹⁾	Wanted signal at –67 dBm, modulated interferer at ±3 MHz, BER = 10 ⁻³	36 / 41 ⁽²⁾		dB
Selectivity, ±4 MHz ⁽¹⁾	Wanted signal at –67 dBm, modulated interferer at ±4 MHz, BER = 10 ⁻³	37 / 45 ⁽²⁾		dB
Selectivity, ±5 MHz or more ⁽¹⁾	Wanted signal at –67 dBm, modulated interferer at ≥ ±5 MHz, BER = 10 ⁻³	40		dB
Selectivity, image frequency ⁽¹⁾	Wanted signal at –67 dBm, modulated interferer at image frequency, BER = 10 ⁻³	33		dB
Selectivity, image frequency ±1 MHz ⁽¹⁾	Note that Image frequency + 1 MHz is the Co- channel -1 MHz. Wanted signal at -67 dBm, modulated interferer at ±1 MHz from image frequency, BER = 10 ⁻³	4 / 41(2)		dB
Out-of-band blocking ⁽³⁾	30 MHz to 2000 MHz	-10		dBm
Out-of-band blocking	2003 MHz to 2399 MHz	-18		dBm
Out-of-band blocking	2484 MHz to 2997 MHz	-12		dBm
Out-of-band blocking	3000 MHz to 12.75 GHz	-2		dBm
Intermodulation	Wanted signal at 2402 MHz, –64 dBm. Two interferers at 2405 and 2408 MHz respectively, at the given power level	-42		dBm
Spurious emissions, 30 to 1000 MHz	Measurement in a 50-Ω single-ended load.	< -59		dBm
Spurious emissions, 1 to 12.75 GHz	Measurement in a $50-\Omega$ single-ended load.	<-47		dBm
RSSI dynamic range		70		dB
RSSI accuracy		±4		dB
2 Mbps (LE 2M)				
Receiver sensitivity	Differential mode. Measured at SMA connector, BER = 10^{-3}	-92		dBm
Receiver sensitivity	Single ended mode. Measured on CC26x1- P3EM-5XS24, at the SMA connector, BER = 10 ⁻³	-92		dBm
Receiver saturation	Differential mode. Measured at SMA connector, BER = 10^{-3}	> 5		dBm



8.10 Bluetooth Low Energy - Receive (RX) (continued)

Measured on the CC26x1-P3EM-7XD24-PA24 reference design with T_c = 25 °C, V_{DDS} = 3.0 V, f_{RF} = 2440 MHz with DC/DC enabled and high power PA connected to V_{DDS} unless otherwise noted.

All measurements are performed at the antenna input with a combined RX and TX path, except for high power PA which is measured at a dedicated antenna connection. All measurements are performed conducted.

PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
Frequency error tolerance	Difference between the incoming carrier frequency and the internally generated carrier frequency	> (-500 / 500)		kHz
Data rate error tolerance	Difference between incoming data rate and the internally generated data rate (37-byte packets)	> (-700 / 750)		ppm
Co-channel rejection ⁽¹⁾	Wanted signal at –67 dBm, modulated interferer in channel,BER = 10 ⁻³	-7		dB
Selectivity, ±2 MHz ⁽¹⁾	Wanted signal at –67 dBm, modulated interferer at ±2 MHz, Image frequency is at –2 MHz, BER = 10^{-3}	8 / 4 ⁽²⁾		dB
Selectivity, ±4 MHz ⁽¹⁾	Wanted signal at -67 dBm, modulated interferer at ± 4 MHz, BER = 10^{-3}	36 / 31 ⁽²⁾		dB
Selectivity, ±6 MHz ⁽¹⁾	Wanted signal at -67 dBm, modulated interferer at ± 6 MHz, BER = 10^{-3}	37 / 36 ⁽²⁾		dB
Selectivity, image frequency ⁽¹⁾	Wanted signal at –67 dBm, modulated interferer at image frequency, BER = 10^{-3}	4		dB
Selectivity, image frequency ±2 MHz ⁽¹⁾	Note that Image frequency + 2 MHz is the Co-channel. Wanted signal at –67 dBm, modulated interferer at ±2 MHz from image frequency, BER = 10 ⁻³	-7 / 36 ⁽²⁾		dB
Out-of-band blocking ⁽³⁾	30 MHz to 2000 MHz	-16		dBm
Out-of-band blocking	2003 MHz to 2399 MHz	-21		dBm
Out-of-band blocking	2484 MHz to 2997 MHz	–15		dBm
Out-of-band blocking	3000 MHz to 12.75 GHz	-12		dBm
Intermodulation	Wanted signal at 2402 MHz, –64 dBm. Two interferers at 2408 and 2414 MHz respectively, at the given power level	-38		dBm

- (1) Numbers given as I/C dB
- (2) X / Y, where X is +N MHz and Y is -N MHz
- (3) Excluding one exception at F_{wanted} / 2, per Bluetooth Specification

Submit Document Feedback

Copyright © 2022 Texas Instruments Incorporated



8.11 Bluetooth Low Energy - Transmit (TX)

Measured on the CC26x1-P3EM-7XD24-PA24 reference design with T_c = 25 °C, V_{DDS} = 3.0 V, f_{RF} = 2440 MHz with DC/DC enabled and high power PA connected to V_{DDS} unless otherwise noted.

All measurements are performed at the antenna input with a combined RX and TX path, except for high power PA which is measured at a dedicated antenna connection. All measurements are performed conducted.

Max output power PA Output po	PARAMETER		TEST CONDITIONS	MIN 7	TYP MAX	UNIT
Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Max output power programmable range play power PA 10 load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dBm Differential mode,	General Parameters					
Differential mode, delivered to a single-ended 50 Ω load through a balun 6 dB mode, which power PA, 10 dBm configuration 9 dB	Max output power, high power PA	Differential mode, delivered to a sing	le-ended 50 Ω load through a balun		20	dBm
ingh power PA, 10 dBm dBm configuration. 3 dBm dBm configuration. 4 dBm dBm dBm configuration. 4 dBm dBm dBm configuration. 4 dBm	Output power programmable range high power PA	Differential mode, delivered to a sing	lle-ended 50 Ω load through a balun		6	dB
Single-ended mode. Measured on CC26x1-P3EM-5XS24, delivered to a single-ended 50 Ω dBm dBm configuration) dBm configuration) dBm configuration dBm configuration) dB	Max output power, high power PA, 10 dBm configuration ⁽³⁾	Differential mode, delivered to a single-ended 50 Ω load through a balun		1	10.5	dBm
programmable range in play power PA, 10 dBm configuration (3) Max output power, regular PA Differential mode, delivered to a single-ended 50 Ω load through a balun Single-ended mode. Measured on CC26x1-P3EM-5XS24, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Single-ended mode. Measured on CC26x1-P3EM-5XS24, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun 26 dBm dBm configuration (3) F<1 GHz, outside restricted bands f<1 GHz, including harmonics F<1 GHz, restricted bands ETSI f<1 GHz, including harmonics F<1 GHz, restricted bands ETSI f<1 GHz, r	Max output power, high power PA, 10 dBm configuration ⁽³⁾		C26x1-P3EM-5XS24, delivered to a single-ended 50 Ω		9	dBm
Differential mode, delivered to a single-ended 50 Ω load through a balun 5 dbm	Output power programmable range high power PA, 10 dBm configuration ⁽³⁾	Differential mode, delivered to a single-ended 50 Ω load through a balun			5	dB
Coutput power programmable range, regular PA Ioad through a balun Differential mode, delivered to a single-ended 50 Ω load through a balun 26 dB	Max output power, regular PA	Differential mode, delivered to a single-ended 50 Ω load through a balun			5	dBm
Differential mode, delivered to a single-ended 50 Ω load through a balun 26 dB	Max output power, regular PA				3	dBm
F < 1 GHz, outside restricted bands F < 1 GHz, including harmonics	Output power programmable range, regular PA	Differential mode, delivered to a single-ended 50 Ω load through a balun			26	dB
Spurious emissions, high-power PA(1) f < 1 GHz, including harmonics	Spurious emissions ar	nd harmonics		II.		
Total Color		f < 1 GHz, outside restricted bands		<	-36	dBm
F > 1 GHz, including harmonics +20 dBm setting -37 dBm -37 dBm -37 dBm -38 dBm -35 dBm -39 dBm -35 dBm -30		f < 1 GHz, restricted bands FCC		<	-55	dBm
Third harmonic high-power PA(2) Third harmonic f < 1 GHz, outside restricted bands high-power PA, 10 dBm configuration(1) (3) f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, high-power PA, 10 dBm configuration(3) Third harmonic f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Third harmonic f < 1 GHz, outside restricted bands FCC f > 1 GHz, outside restricted bands f < 1 GHz, outside restricted bands f < 1 GHz, restricted bands f < 1 GHz, outside restricted bands f < 1 GHz, restricted bands f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics F < 1 GHz, restricted bands FCC f > 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, Second harmonic Second harmonic Second harmonic Second harmonic General Adam Ad	g., p =	f > 1 GHz, including harmonics	+20 dBm setting		-37	dBm
Spurious emissions, high-power PA, 10	Harmonics,	Second harmonic			-35	dBm
Spurious emissions, high-power PA, 10 dBm configuration(1) (3)	high-power PA ⁽²⁾	Third harmonic			-42	dBm
high-power PA, 10 dBm configuration(1) (3)		f < 1 GHz, outside restricted bands		<	-36	dBm
dBm configuration(1) (3) f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, high-power PA, 10 dBm configuration(3) Third harmonic f < 1 GHz, outside restricted bands f < 1 GHz, outside restricted bands f < 1 GHz, restricted bands ETSI f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, Second harmonic f < 1 GHz, outside restricted bands ETSI f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, Second harmonic f < 1 GHz, outside restricted bands ETSI f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, Second harmonic f < 1 GHz, outside restricted bands ETSI f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, Second harmonic	Spurious emissions,	f < 1 GHz, restricted bands ETSI		<	-54	dBm
Harmonics, high-power PA, 10 dBm configuration(3) Second harmonic Third harmonic F 1 GHz, including narmonics Second harmonic Third harmonic F 1 GHz, outside restricted bands F 1 GHz, outside restricted bands F 1 GHz, restricted bands ETSI F 1 GHz, restricted bands ETSI F 1 GHz, restricted bands ETSI F 1 GHz, restricted bands F 2 GBm setting F 3 GBm ABm ABm ABm ABm ABm ABm ABm	dBm configuration ⁽¹⁾ (3)	f < 1 GHz, restricted bands FCC	(2)	<	-55	dBm
high-power PA, 10 dBm configuration(3) Third harmonic f < 1 GHz, outside restricted bands f < 1 GHz, restricted bands ETSI f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, Second harmonic Third harmonic f < 1 GHz, outside restricted bands ETSI f < 1 GHz, restricted bands ETSI f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, Second harmonic		f > 1 GHz, including harmonics	7+10 dBm setting ⁽³⁾		-41	dBm
Third harmonic Third harmonic C - 42 dBm	Harmonics,	Second harmonic		<	-42	dBm
Spurious emissions, regular PA f < 1 GHz, restricted bands ETSI f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, Second harmonic f < 1 GHz, restricted bands ETSI f < 1 GHz, including harmonics +5 dBm setting -54 dBm -55 dBm -42 dBm	dBm configuration ⁽³⁾	Third harmonic		<	-42	dBm
regular PA f < 1 GHz, restricted bands FCC f > 1 GHz, including harmonics Harmonics, Second harmonic +5 dBm setting <-42 dBm <-42 dBm		f < 1 GHz, outside restricted bands		<	-36	dBm
f > 1 GHz, including harmonics f > 1 GHz, including harmonics +5 dBm setting <-42 dBm <-42 dBm	Spurious emissions,	f < 1 GHz, restricted bands ETSI		<	-54	dBm
f > 1 GHz, including harmonics < -42 dBm Harmonics, Second harmonic <-42 dBm	regular PA	f < 1 GHz, restricted bands FCC	+5 dPm cotting	<	-55	dBm
Training,		f > 1 GHz, including harmonics	- +5 dom setting	<	-42	dBm
regular PA Third harmonic <-42 dBm	Harmonics,	Second harmonic		<	-42	dBm
	regular PA	Third harmonic		<	-42	dBm

⁽¹⁾ To ensure margins for passing FCC band edge requirements at 2483.5 MHz, a lower than maximum output-power setting or less than 100% duty cycle may be used when operating at the upper Bluetooth Low Energy channel(s).

⁽²⁾ To ensure margins for passing FCC requirements for harmonic emission, duty cycling may be required. The CC2651P3 LaunchPad reference design should also be reviewed as the filter provides higher attenuation of harmonics compared to the CC26x1-P3EM-XD24-PA24 reference design.

⁽³⁾ Measured on evaluation board as described in www.ti.com/lit/pdf/swra636.



8.12 Zigbee - IEEE 802.15.4-2006 2.4 GHz (OQPSK DSSS1:8, 250 kbps) - RX

Measured on the CC26x1-P3EM-7XD24-PA24 reference design with T_c = 25 °C, V_{DDS} = 3.0 V, f_{RF} = 2440 MHz with DC/DC enabled and high power PA connected to V_{DDS} unless otherwise noted.

All measurements are performed at the antenna input with a combined RX and TX path, except for high power PA which is measured at a dedicated antenna connection. All measurements are performed conducted.

PARAMETER	TEST CONDITIONS	MIN TYP MAX	UNIT
General Parameters			
Receiver sensitivity	Differential mode PER = 1%	-100	dBm
Receiver sensitivity	Single-Ended mode. Measured on CC26x1-P3EM-5XS24 at the SMA connector. PER = 1%	-99	dBm
Receiver saturation	PER = 1%	> 5	dBm
Adjacent channel rejection	Wanted signal at –82 dBm, modulated interferer at ±5 MHz, PER = 1%	36	dB
Alternate channel rejection	Wanted signal at –82 dBm, modulated interferer at ±10 MHz, PER = 1%	57	dB
Channel rejection, ±15 MHz or more	Wanted signal at –82 dBm, undesired signal is IEEE 802.15.4 modulated channel, stepped through all channels 2405 to 2480 MHz, PER = 1%	59	dB
Blocking and desensitization, 5 MHz from upper band edge	Wanted signal at –97 dBm (3 dB above the sensitivity level), CW jammer, PER = 1%	57	dB
Blocking and desensitization, 10 MHz from upper band edge	Wanted signal at –97 dBm (3 dB above the sensitivity level), CW jammer, PER = 1%	63	dB
Blocking and desensitization, 20 MHz from upper band edge	Wanted signal at –97 dBm (3 dB above the sensitivity level), CW jammer, PER = 1%	63	dB
Blocking and desensitization, 50 MHz from upper band edge	Wanted signal at –97 dBm (3 dB above the sensitivity level), CW jammer, PER = 1%	66	dB
Blocking and desensitization, –5 MHz from lower band edge	Wanted signal at –97 dBm (3 dB above the sensitivity level), CW jammer, PER = 1%	60	dB
Blocking and desensitization, –10 MHz from lower band edge	Wanted signal at –97 dBm (3 dB above the sensitivity level), CW jammer, PER = 1%	60	dB
Blocking and desensitization, –20 MHz from lower band edge	Wanted signal at –97 dBm (3 dB above the sensitivity level), CW jammer, PER = 1%	63	dB
Blocking and desensitization, –50 MHz from lower band edge	Wanted signal at –97 dBm (3 dB above the sensitivity level), CW jammer, PER = 1%	65	dB
Spurious emissions, 30 MHz to 1000 MHz	Measurement in a $50-\Omega$ single-ended load ⁽¹⁾	-66	dBm
Spurious emissions, 1 GHz to 12.75 GHz	Measurement in a 50-Ω single-ended load ⁽¹⁾	-53	dBm
Frequency error tolerance	Difference between the incoming carrier frequency and the internally generated carrier frequency	> 350	ppm
Symbol rate error tolerance	Difference between incoming symbol rate and the internally generated symbol rate	> 1000	ppm
RSSI dynamic range		95	dB
RSSI accuracy		±4	dB

⁽¹⁾ Suitable for systems targeting compliance with EN 300 328, EN 300 440 class 2, FCC CFR47, Part 15 and ARIB STD-T-66

Product Folder Links: CC2651P3



8.13 Zigbee - IEEE 802.15.4-2006 2.4 GHz (OQPSK DSSS1:8, 250 kbps) - TX

Measured on the CC26x1-P3EM-7XD24-PA24 reference design with T_c = 25 °C, V_{DDS} = 3.0 V, f_{RF} = 2440 MHz with DC/DC enabled and high power PA connected to V_{DDS} unless otherwise noted.

All measurements are performed at the antenna input with a combined RX and TX path, except for high power PA which is measured at a dedicated antenna connection. All measurements are performed conducted.

PARAMETER		TEST CONDITIONS	MIN TYP	MAX	UNIT
General Parameters					
Max output power, high power PA	Differential mode, delivered to a s	ingle-ended 50-Ω load through a balun	20		dBm
Output power programmable range, high power PA	Differential mode, delivered to a s	ingle-ended 50-Ω load through a balun	6		dB
Max output power, high power PA, 10 dBm configuration ⁽⁴⁾	Differential mode, delivered to a single-ended 50-Ω load through a balun		10.5		dBm
Max output power, high power PA, 10 dBm configuration ⁽⁴⁾	Single-ended mode. Measured on Ω load through a balun				dBm
Output power programmable range, high power PA, 10 dBm configuration ⁽⁴⁾	Differential mode, delivered to a s	ferential mode, delivered to a single-ended 50- Ω load through a balun			dB
Max output power, regular PA	Differential mode, delivered to a s	ingle-ended 50-Ω load through a balun	5		dBm
Output power programmable range, regular PA	Differential mode, delivered to a s	ingle-ended 50- Ω load through a balun	26		dB
Spurious emissions and	harmonics				
Spurious amissions	f < 1 GHz, outside restricted bands		< -39		dBm
igh-power PA ⁽²⁾ Harmonics,	f < 1 GHz, restricted bands FCC	1	< -49		dBm
	f > 1 GHz, including harmonics	+20 dBm setting	-40		dBm
Harmonics.	Second harmonic	1	-35		dBm
high-power PA ⁽³⁾	Third harmonic	1	-42		dBm
	f < 1 GHz, outside restricted bands		< -36		dBm
	f < 1 GHz, restricted bands ETSI		< -47		dBm
Coutput power PA Coutput power programmable range, high power PA Max output power, high power PA, 10 dBm configuration (4) Max output power, high power PA, 10 dBm configuration (4) Coutput power programmable range, high power PA, 10 dBm configuration (4) Max output power, regular PA Coutput power programmable range, regular PA Spurious emissions and Spurious emissions and Spurious emissions, high-power PA (3) Harmonics, high-power PA, 10 dBm configuration (2) (4) Harmonics, high-power PA, 10 dBm configuration (4) Espurious emissions, regular PA Beguin PA Harmonics emissions, high-power PA, 10 dBm configuration (4) Espurious emissions, regular PA Error vector magnitude, high power PA, 10 dBm configuration (4) Error vector magnitude, high power PA, 10 dBm configuration (4) Error vector magnitude, high power PA, 10 dBm configuration (4) Error vector magnitude, high power PA, 10 dBm configuration (4) Error vector magnitude Error vector magnitude Error vector magnitude Error vector magnitude	f < 1 GHz, restricted bands FCC	+10 dBm setting ⁽⁴⁾	< -55		dBm
	f > 1 GHz, including harmonics		-42		dBm
	Second harmonic		< -42		dBm
high-power PA, 10 dBm configuration ⁽⁴⁾	It power, high bifferential mode, delivered to a single-ended 50-Ω load through a balun wer able range, rPA it power, high 10 dBm on on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferential mode, delivered to a single-ended 50-Ω load through a balun on 60 bifferenti	< -42		dBm	
			< -36		dBm
Spurious emissions,	f < 1 GHz, restricted bands ETSI	-	< -47		dBm
Spurious emissions, ligh-power PA ⁽²⁾ Harmonics, ligh-power PA ⁽³⁾ Spurious emissions, ligh-power PA, 10 dBm configuration ⁽²⁾ (4) Harmonics, ligh-power PA, 10 dBm configuration ⁽⁴⁾ Spurious emissions, ligh-power PA (1) Spurious emissions, ligh-power PA (1) Estarmonics, ligh-power PA (1)	f < 1 GHz, restricted bands FCC	+5 dBm setting	< -55		dBm
	f > 1 GHz, including harmonics		< -42		dBm
Harmonics,	Second harmonic		< -42		dBm
regular PA	Third harmonic		< -42		dBm
IEEE 802.15.4-2006 2.4 (GHz (OQPSK DSSS1:8, 250 kbps)				
Error vector magnitude, high power PA	+20 dBm setting		2		%
Error vector magnitude, high power PA, 10 dBm configuration ⁽⁴⁾	+10 dBm setting		2		%
Error vector magnitude Regular PA	+5 dBm setting		2		%

⁽¹⁾ To ensure margins for passing FCC band edge requirements at 2483.5 MHz, a lower than maximum output-power setting or less than 100% duty cycle may be used when operating at 2480 MHz.



- (2) To ensure margins for passing FCC band edge requirements at 2483.5 MHz, a lower than maximum output-power setting or less than 100% duty cycle may be used when operating at the upper 802.15.4 channel(s).
- (3) To ensure margins for passing FCC requirements for harmonic emission, duty cycling may be required. The CC2651P3 LaunchPad reference design should also be reviewed as the filter provides higher attenuation of harmonics compared to the CC26x1-P3EM-7XD24-PA24 reference design.
- (4) Measured on evaluation board as described in https://www.ti.com/lit/pdf/swra636.

8.14 Timing and Switching Characteristics

8.14.1 Reset Timing

PARAMETER	MIN	TYP MAX	UNIT
RESET_N low duration	1		μs

8.14.2 Wakeup Timing

Measured over operating free-air temperature with V_{DDS} = 3.0 V (unless otherwise noted). The times listed here do not include software overhead.

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
MCU, Reset to Active ⁽¹⁾		8	50 - 4000		μs
MCU, Shutdown to Active ⁽¹⁾		8	50 - 4000		μs
MCU, Standby to Active			160		μs
MCU, Active to Standby			36		μs
MCU, Idle to Active			14		μs

⁽¹⁾ The wakeup time is dependent on remaining charge on VDDR capacitor when starting the device, and thus how long the device has been in Reset or Shutdown before starting up again. The wake up time increases with a higher capacitor value.

8.14.3 Clock Specifications

8.14.3.1 48 MHz Crystal Oscillator (XOSC_HF)

Measured on a Texas Instruments reference design with T_c = 25 °C, V_{DDS} = 3.0 V, unless otherwise noted. (1)

	PARAMETER	MIN	TYP	MAX	UNIT
	Crystal frequency		48		MHz
ESR	Equivalent series resistance 6 pF < C _L ≤ 9 pF		20	60	Ω
ESR	Equivalent series resistance 5 pF < $C_L \le 6$ pF			80	Ω
L _M	Motional inductance, relates to the load capacitance that is used for the crystal (C _L in Farads) ⁽⁵⁾		$< 3 \times 10^{-25} / C_L^2$		Н
C _L	Crystal load capacitance ⁽⁴⁾	5	7 ⁽³⁾	9	pF
	Start-up time ⁽²⁾		200		μs

- (1) Probing or otherwise stopping the crystal while the DC/DC converter is enabled may cause permanent damage to the device.
- (2) Start-up time using the TI-provided power driver. Start-up time may increase if driver is not used.
- (3) On-chip default connected capacitance including reference design parasitic capacitance. Connected internal capacitance is changed through software in the Customer Configuration section (CCFG).
- (4) Adjustable load capacitance is integrated into the device. External load capacitors are required for systems targeting compliance with certain regulations. See the device errata for further details.
- (5) The crystal manufacturer's specification must satisfy this requirement for proper operation.

8.14.3.2 48 MHz RC Oscillator (RCOSC HF)

Measured on a Texas Instruments reference design with T_c = 25 °C, V_{DDS} = 3.0 V, unless otherwise noted.

	MIN	TYP	MAX	UNIT
Frequency		48		MHz
Uncalibrated frequency accuracy		±1		%
Calibrated frequency accuracy ⁽¹⁾		±0.25		%
Start-up time		5		μs

(1) Accuracy relative to the calibration source (XOSC_HF)

Product Folder Links: CC2651P3



8.14.3.3 32.768 kHz Crystal Oscillator (XOSC_LF)

Measured on a Texas Instruments reference design with T_c = 25 °C, V_{DDS} = 3.0 V, unless otherwise noted.

		MIN	TYP	MAX	UNIT
	Crystal frequency		32.768		kHz
ESR	Equivalent series resistance		30	100	kΩ
C _L	Crystal load capacitance	6	7 ⁽¹⁾	12	pF

Default load capacitance using TI reference designs including parasitic capacitance. Crystals with different load capacitance may be used.

8.14.3.4 32 kHz RC Oscillator (RCOSC_LF)

Measured on a Texas Instruments reference design with T_c = 25 °C, V_{DDS} = 3.0 V, unless otherwise noted.

	<u> </u>				
		MIN	TYP	MAX	UNIT
Calibrated frequ	uency		32.8		kHz
Calibrated RTC variation ⁽¹⁾	Calibrated periodically against XOSC_HF ⁽²⁾		±600 ⁽³⁾		ppm
Temperature co	pefficient.		50		ppm/°C

- (1) When using RCOSC_LF as source for the low frequency system clock (SCLK_LF), the accuracy of the SCLK_LF-derived Real Time Clock (RTC) can be improved by measuring RCOSC_LF relative to XOSC_HF and compensating for the RTC tick speed. This functionality is available through the TI-provided Power driver.
- (2) TI driver software calibrates the RTC every time XOSC_HF is enabled.
- (3) Some device's variation can exceed 1000 ppm. Further calibration will not improve variation.

8.14.4 Synchronous Serial Interface (SSI) Characteristics

8.14.4.1 Synchronous Serial Interface (SSI) Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER NO.		PARAMETER	MIN	ТҮР	MAX	UNIT
S1	t _{clk_per}	SSICIk cycle time	12		65024	System Clocks (2)
S2 ⁽¹⁾	t _{clk_high}	SSICIk high time		0.5		t _{clk_per}
S3 ⁽¹⁾	t _{clk_low}	SSICIk low time		0.5		t _{clk_per}

- (1) Refer to SSI timing diagrams Figure 8-1, Figure 8-2, and Figure 8-3.
- (2) When using the TI-provided Power driver, the SSI system clock is always 48 MHz.

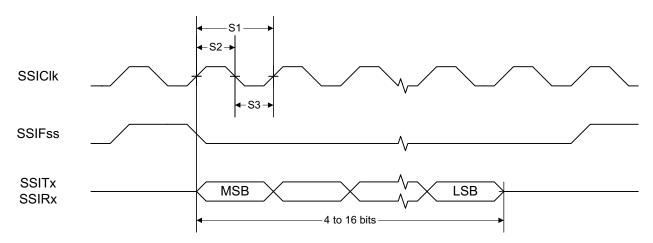


Figure 8-1. SSI Timing for TI Frame Format (FRF = 01), Single Transfer Timing Measurement



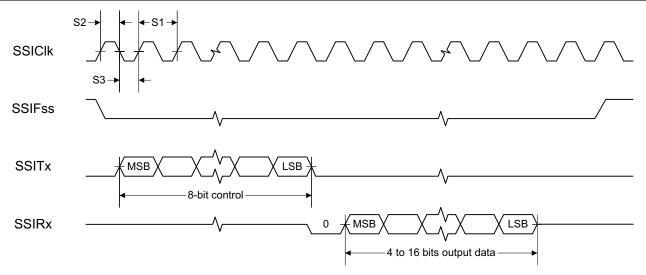


Figure 8-2. SSI Timing for MICROWIRE Frame Format (FRF = 10), Single Transfer

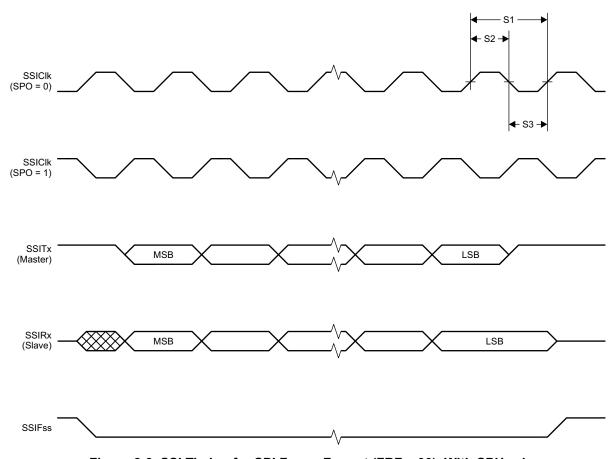


Figure 8-3. SSI Timing for SPI Frame Format (FRF = 00), With SPH = 1

8.14.5 UART

8.14.5.1 UART Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER	MIN	TYP	MAX	UNIT
UART rate			3	MBaud



8.15 Peripheral Characteristics

8.15.1 ADC

8.15.1.1 Analog-to-Digital Converter (ADC) Characteristics

 T_c = 25 °C, V_{DDS} = 3.0 V and voltage scaling enabled, unless otherwise noted.⁽¹⁾ Performance numbers require use of offset and gain adjustements in software by TI-provided ADC drivers.

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
	Input voltage range		0	VDDS	V
	Resolution		12		Bits
	Sample Rate			200	ksps
	Offset	Internal 4.3 V equivalent reference ⁽²⁾	-0.24		LSB
	Gain error	Internal 4.3 V equivalent reference ⁽²⁾	7.14		LSB
DNL ⁽⁴⁾	Differential nonlinearity		>–1		LSB
INL	Integral nonlinearity		±4		LSB
		Internal 4.3 V equivalent reference ⁽²⁾ , 200 kSamples/s, 9.6 kHz input tone	9.8		
		Internal 4.3 V equivalent reference ⁽²⁾ , 200 kSamples/s, 9.6 kHz input tone, DC/DC enabled	9.8		
		VDDS as reference, 200 kSamples/s, 9.6 kHz input tone	10.1		
ENOB	Effective number of bits	Internal reference, voltage scaling disabled, 32 samples average (software), 200 kSamples/s, 300 Hz input tone	11.1		Bits
		Internal reference, voltage scaling disabled, 14-bit mode, 200 kSamples/s, 300 Hz input tone (5)	11.3		
		Internal reference, voltage scaling disabled, 15-bit mode, 200 kSamples/s, 300 Hz input tone ⁽⁵⁾	11.6		
	Total harmonic distortion	Internal 4.3 V equivalent reference ⁽²⁾ , 200 kSamples/s, 9.6 kHz input tone	-65		
THD		VDDS as reference, 200 kSamples/s, 9.6 kHz input tone	-70		dB
		Internal reference, voltage scaling disabled, 32 samples average, 200 kSamples/s, 300 Hz input tone	-72		
		Internal 4.3 V equivalent reference ⁽²⁾ , 200 kSamples/s, 9.6 kHz input tone	60		
SINAD,	Signal-to-noise and	VDDS as reference, 200 kSamples/s, 9.6 kHz input tone	63		dB
SNDR	distortion ratio	Internal reference, voltage scaling disabled, 32 samples average (software), 200 kSamples/s, 300 Hz input tone	68		
		Internal 4.3 V equivalent reference ⁽²⁾ , 200 kSamples/s, 9.6 kHz input tone	70		
SFDR	Spurious-free dynamic range	VDDS as reference, 200 kSamples/s, 9.6 kHz input tone	73		dB
OI DIX	opunous nos dynamis range	Internal reference, voltage scaling disabled, 32 samples average (software), 200 kSamples/s, 300 Hz input tone	75		u.b
	Conversion time	Serial conversion, time-to-output, 24 MHz clock	50		Clock Cycles
	Current consumption	Internal 4.3 V equivalent reference ⁽²⁾	0.39		mA
	Current consumption	VDDS as reference	0.56		mA
	Reference voltage	Equivalent fixed internal reference (input voltage scaling enabled). For best accuracy, the ADC conversion should be initiated through the TI-RTOS API in order to include the gain/ offset compensation factors stored in FCFG1	4.3(2) (3)		V
	Reference voltage	Fixed internal reference (input voltage scaling disabled). For best accuracy, the ADC conversion should be initiated through the TI-RTOS API in order to include the gain/offset compensation factors stored in FCFG1. This value is derived from the scaled value (4.3 V) as follows: $V_{ref} = 4.3 \text{ V} \times 1408 \text{ / } 4095$	1.48		V
	Reference voltage	VDDS as reference, input voltage scaling enabled	VDDS		V
	Reference voltage	VDDS as reference, input voltage scaling disabled	VDDS / 2.82 ⁽³⁾		V



8.15.1.1 Analog-to-Digital Converter (ADC) Characteristics (continued)

 T_c = 25 °C, V_{DDS} = 3.0 V and voltage scaling enabled, unless otherwise noted.⁽¹⁾

Performance numbers require use of offset and gain adjustements in software by TI-provided ADC drivers.

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	200 kSamples/s, voltage scaling enabled. Capacitive input, Input impedance depends on sampling frequency and sampling time		>1		МΩ

- (1) Using IEEE Std 1241-2010 for terminology and test methods
- (2) Input signal scaled down internally before conversion, as if voltage range was 0 to 4.3 V
- (3) Applied voltage must be within Absolute Maximum Ratings at all times
- (4) No missing codes
- (5) ADC_output = $\Sigma(4^n \text{ samples}) >> n$, n = desired extra bits

8.15.2 DAC

8.15.2.1 Digital-to-Analog Converter (DAC) Characteristics

 T_c = 25 °C, V_{DDS} = 3.0 V, unless otherwise noted.

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Genera	l Parameters					
	Resolution			8		Bits
		Any load, any V _{REF} , pre-charge OFF, DAC charge-pump ON	1.8		3.8	
V_{DDS}	Supply voltage	External Load ⁽⁴⁾ , any V _{REF} , pre-charge OFF, DAC charge-pump OFF	2.0		3.8	V
		Any load, V _{REF} = DCOUPL, pre-charge ON	2.6		3.8	
F _{DAC}	Clock froquency	Buffer ON (recommended for external load)	16		250	kHz
FDAC	Clock frequency	Buffer OFF (internal load)	16		1000	KΠZ
	Voltage output settling time	V _{REF} = VDDS, buffer OFF, internal load		13		1/5
	Voltage output settling time	V _{REF} = VDDS, buffer ON, external capacitive load = 20 pF ⁽³⁾		13.8		1 / F _{DAC}
	External capacitive load			20	200	pF
	External resistive load		10			МΩ
	Short circuit current				400	μΑ
	Max output impedance Vref = VDDS, buffer ON, CLK 250 kHz	VDDS = 3.8 V, DAC charge-pump OFF		50.8		
		VDDS = 3.0 V, DAC charge-pump ON		51.7		
		VDDS = 3.0 V, DAC charge-pump OFF		53.2		
Z _{MAX}		VDDS = 2.0 V, DAC charge-pump ON		48.7		kΩ
		VDDS = 2.0 V, DAC charge-pump OFF		70.2		
		VDDS = 1.8 V, DAC charge-pump ON		46.3		
		VDDS = 1.8 V, DAC charge-pump OFF		88.9		
nternal	Load - Continuous Time Com	parator / Low Power Clocked Comparator			'	
DAII	Differential nonlinearity	V _{REF} = VDDS, load = Continuous Time Comparator or Low Power Clocked Comparator F _{DAC} = 250 kHz		±1		L CD(1)
DNL	Differential nonlinearity	V _{REF} = VDDS, load = Continuous Time Comparator or Low Power Clocked Comparator F _{DAC} = 16 kHz		±1.2		LSB ⁽¹⁾
		V _{REF} = VDDS = 3.8 V		±0.64		
		V _{REF} = VDDS= 3.0 V		±0.81		
	Offset error ⁽²⁾	V _{REF} = VDDS = 1.8 V		±1.27		L CD(1)
	Load = Continuous Time Comparator	V _{REF} = DCOUPL, pre-charge ON		±3.43		LSB ⁽¹⁾
		V _{REF} = DCOUPL, pre-charge OFF		±2.88		
		V _{REF} = ADCREF		±2.37		

Product Folder Links: CC2651P3



8.15.2.1 Digital-to-Analog Converter (DAC) Characteristics (continued)

T_c = 25 °C, V_{DDS} = 3.0 V, unless otherwise noted.

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
		V _{REF} = VDDS= 3.8 V	±0.78		
		V _{REF} = VDDS = 3.0 V	±0.77		
	Offset error ⁽²⁾ Load = Low Power Clocked	V _{REF} = VDDS= 1.8 V	±3.46		LSB ⁽¹⁾
	Comparator	V _{REF} = DCOUPL, pre-charge ON	±3.44		LOB
		V _{REF} = DCOUPL, pre-charge OFF	±4.70		
		V _{REF} = ADCREF	±4.11		
		V _{REF} = VDDS = 3.8 V	±1.53		
		V _{REF} = VDDS = 3.0 V	±1.71		
	Max code output voltage variation ⁽²⁾	V _{REF} = VDDS= 1.8 V	±2.10		L OD(1)
	Load = Continuous Time Comparator	V _{REF} = DCOUPL, pre-charge ON	±6.00		LSB ⁽¹⁾
		V _{REF} = DCOUPL, pre-charge OFF	±3.85		
		V _{REF} = ADCREF	±5.84		
		V _{REF} = VDDS= 3.8 V	±2.92		
		V _{REF} =VDDS= 3.0 V	±3.06		
	Max code output voltage variation ⁽²⁾	V _{REF} = VDDS= 1.8 V	±3.91		
	Load = Low Power Clocked	V _{REF} = DCOUPL, pre-charge ON	±7.84		LSB ⁽¹⁾
	Comparator	V _{RFF} = DCOUPL, pre-charge OFF	±4.06		
		V _{REF} = ADCREF	±6.94		
		V _{REF} = VDDS = 3.8 V, code 1	0.03		
		V _{RFF} = VDDS = 3.8 V, code 255	3.62		
		V _{REF} = VDDS= 3.0 V, code 1	0.02		
		V _{REF} = VDDS= 3.0 V, code 255	2.86		
		V _{REF} = VDDS= 1.8 V, code 1	0.01		
	Output voltage range ⁽²⁾	V _{REF} = VDDS = 1.8 V, code 255	1.71		
	Load = Continuous Time	V _{REF} = DCOUPL, pre-charge OFF, code 1	0.01		V
	Comparator	V _{REF} = DCOUPL, pre-charge OFF, code 255	1.21		
		V _{REF} = DCOUPL, pre-charge ON, code 1	1.27		
		V _{REF} = DCOUPL, pre-charge ON, code 255	2.46		
		V _{REF} = DOCREF, code 1	0.01		
		V _{REF} = ADCREF, code 255	1.41		
		V _{REF} = VDDS = 3.8 V, code 1	0.03		
		V _{REF} = VDDS = 3.8 V, code 1	3.61		
		V _{REF} = VDDS= 3.0 V, code 1	0.02		
		V _{REF} = VDDS= 3.0 V, code 1 V _{REF} = VDDS= 3.0 V, code 255	2.85		
		V _{REF} = VDDS = 1.8 V, code 1	0.01		
	Output voltage range ⁽²⁾	V _{REF} = VDDS = 1.8 V, code 1 V _{REF} = VDDS = 1.8 V, code 255	1.71		
	Load = Low Power Clocked				V
	Comparator	V _{REF} = DCOUPL, pre-charge OFF, code 1 V _{REF} = DCOUPL, pre-charge OFF, code 255	0.01		
		· · · · · · · · · · · · · · · · · · ·			
		V _{REF} = DCOUPL, pre-charge ON, code 1	1.27		
		V _{REF} = DCOUPL, pre-charge ON, code 255	2.46		
		V _{REF} = ADCREF, code 1	0.01		
		V _{REF} = ADCREF, code 255	1.41		
ernal	Load (Keysight 34401A Multi	,			
		V _{REF} = VDDS, F _{DAC} = 250 kHz	±1		
	Integral nonlinearity	V _{REF} = DCOUPL, F _{DAC} = 250 kHz	±1		LSB ⁽¹⁾
		V _{REF} = ADCREF, F _{DAC} = 250 kHz	±1		



8.15.2.1 Digital-to-Analog Converter (DAC) Characteristics (continued)

 T_c = 25 °C, V_{DDS} = 3.0 V, unless otherwise noted.

PARAMETER	TEST CONDITIONS	MIN TYP	MAX UN	NIT
	V _{REF} = VDDS= 3.8 V	±0.20		
	V _{REF} = VDDS= 3.0 V	±0.25		
Offset error	V _{REF} = VDDS = 1.8 V	±0.45	LSI	D(1)
Oliset error	V _{REF} = DCOUPL, pre-charge ON	±1.55	LSI	D(· /
	V _{REF} = DCOUPL, pre-charge OFF	±1.30		
	V _{REF} = ADCREF	±1.10		
	V _{REF} = VDDS= 3.8 V	±0.60		
	V _{REF} = VDDS= 3.0 V	±0.55		
Max code output voltage	V _{REF} = VDDS= 1.8 V	±0.60	1.01	D(1)
variation	V _{REF} = DCOUPL, pre-charge ON	±3.45	LSI	LSB ⁽¹⁾
	V _{REF} = DCOUPL, pre-charge OFF	±2.10		
	V _{REF} = ADCREF	±1.90		
	V _{REF} = VDDS = 3.8 V, code 1	0.03		
	V _{REF} = VDDS = 3.8 V, code 255	3.61		
	V _{REF} = VDDS = 3.0 V, code 1	0.02		
	V _{REF} = VDDS= 3.0 V, code 255	2.85		
	V _{REF} = VDDS= 1.8 V, code 1	0.02		
Output voltage range Load = Low Power Clocked	V _{REF} = VDDS = 1.8 V, code 255	1.71	,	/
Comparator	V _{REF} = DCOUPL, pre-charge OFF, code 1	0.02		,
·	V _{REF} = DCOUPL, pre-charge OFF, code 255	1.20		
	V _{REF} = DCOUPL, pre-charge ON, code 1	1.27		
	V _{REF} = DCOUPL, pre-charge ON, code 255	2.46		
	V _{REF} = ADCREF, code 1	0.02		
	V _{REF} = ADCREF, code 255	1.42		

- 1 LSB (V_{REF} 3.8 V/3.0 V/1.8 V/DCOUPL/ADCREF) = 14.10 mV/11.13 mV/6.68 mV/4.67 mV/5.48 mV
- (2)
- Includes comparator offset
 A load > 20 pF will increases the settling time (3) A load > 20 pF will increases(4) Keysight 34401A Multimeter

Submit Document Feedback

Copyright © 2022 Texas Instruments Incorporated

8.15.3 Temperature and Battery Monitor

8.15.3.1 Temperature Sensor

Measured on a Texas Instruments reference design with T_c = 25 °C, V_{DDS} = 3.0 V, unless otherwise noted.

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Resolution			2		°C
Accuracy	-40 °C to 0 °C		±4.0		°C
Accuracy	0 °C to 105 °C		±2.5		°C
Supply voltage coefficient ⁽¹⁾			3.9		°C/V

(1) The temperature sensor is automatically compensated for VDDS variation when using the TI-provided driver.

8.15.3.2 Battery Monitor

Measured on a Texas Instruments reference design with T_c = 25 °C, unless otherwise noted.

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Resolution			25		mV
Range		1.8		3.8	V
Integral nonlinearity (max)			23		mV
Accuracy	VDDS = 3.0 V		22.5		mV
Offset error			-32		mV
Gain error			-1		%

8.15.4 Comparator

8.15.4.1 Continuous Time Comparator

 $T_c = 25$ °C, $V_{DDS} = 3.0$ V, unless otherwise noted.

C , BBC ,					
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Input voltage range ⁽¹⁾		0		V_{DDS}	V
Offset	Measured at V _{DDS} / 2		±5		mV
Decision time	Step from –10 mV to 10 mV		0.78		μs
Current consumption	Internal reference		9.2		μA

⁽¹⁾ The input voltages can be generated externally and connected throughout I/Os or an internal reference voltage can be generated using the DAC

8.15.5 GPIO

8.15.5.1 GPIO DC Characteristics

PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
T _A = 25 °C, V _{DDS} = 1.8 V				
GPIO VOH at 8 mA load	IOCURR = 2, high-drive GPIOs only			V
GPIO VOL at 8 mA load	IOCURR = 2, high-drive GPIOs only	0.24		V
GPIO VOH at 4 mA load	IOCURR = 1	1.59		V
GPIO VOL at 4 mA load	IOCURR = 1	0.21		V
GPIO pullup current	Input mode, pullup enabled, Vpad = 0 V	73		μA
GPIO pulldown current	Input mode, pulldown enabled, Vpad = VDDS	19		μA
GPIO low-to-high input transition, with hysteresis	IH = 1, transition voltage for input read as $0 \rightarrow 1$	1.08		V
GPIO high-to-low input transition, with hysteresis	IH = 1, transition voltage for input read as $1 \rightarrow 0$	0.73		V
GPIO input hysteresis	IH = 1, difference between $0 \rightarrow 1$ and $1 \rightarrow 0$ points	0.35		V
T _A = 25 °C, V _{DDS} = 3.0 V				
GPIO VOH at 8 mA load	IOCURR = 2, high-drive GPIOs only	2.59		V
GPIO VOL at 8 mA load	IOCURR = 2, high-drive GPIOs only	0.42		V
GPIO VOH at 4 mA load	IOCURR = 1	2.63		V
GPIO VOL at 4 mA load	IOCURR = 1	0.40		V



8.15.5.1 GPIO DC Characteristics (continued)

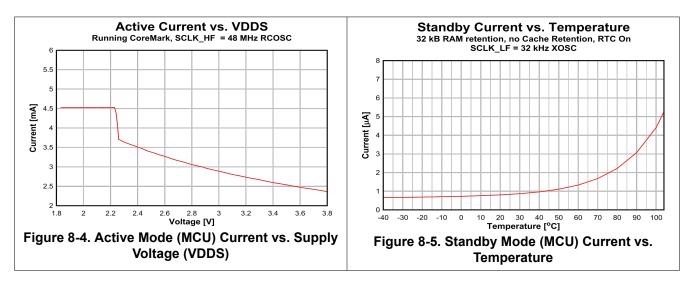
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
T _A = 25 °C, V _{DDS} = 3.8 V							
GPIO pullup current	Input mode, pullup enabled, Vpad = 0 V		282		μA		
GPIO pulldown current	Input mode, pulldown enabled, Vpad = VDDS		110		μA		
GPIO low-to-high input transition, with hysteresis	IH = 1, transition voltage for input read as $0 \rightarrow 1$		1.97		V		
GPIO high-to-low input transition, with hysteresis	IH = 1, transition voltage for input read as $1 \rightarrow 0$		1.55		V		
GPIO input hysteresis	IH = 1, difference between $0 \rightarrow 1$ and $1 \rightarrow 0$ points		0.42		V		
T _A = 25 °C			-				
VIH	Lowest GPIO input voltage reliably interpreted as a High	0.8*V _{DDS}			V		
VIL	Highest GPIO input voltage reliably interpreted as a Low		0	.2*V _{DDS}	٧		



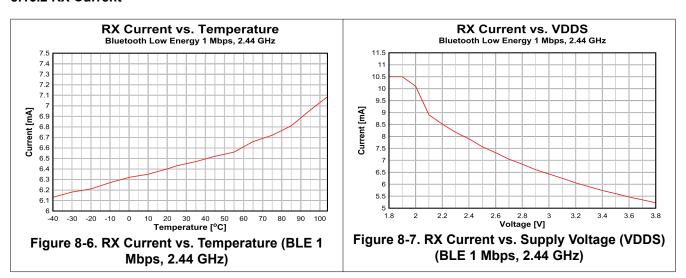
8.16 Typical Characteristics

All measurements in this section are done with T_c = 25 °C and V_{DDS} = 3.0 V, unless otherwise noted. See *Recommended Operating Conditions*, Section 8.3, for device limits. Values exceeding these limits are for reference only.

8.16.1 MCU Current



8.16.2 RX Current





8.16.3 TX Current

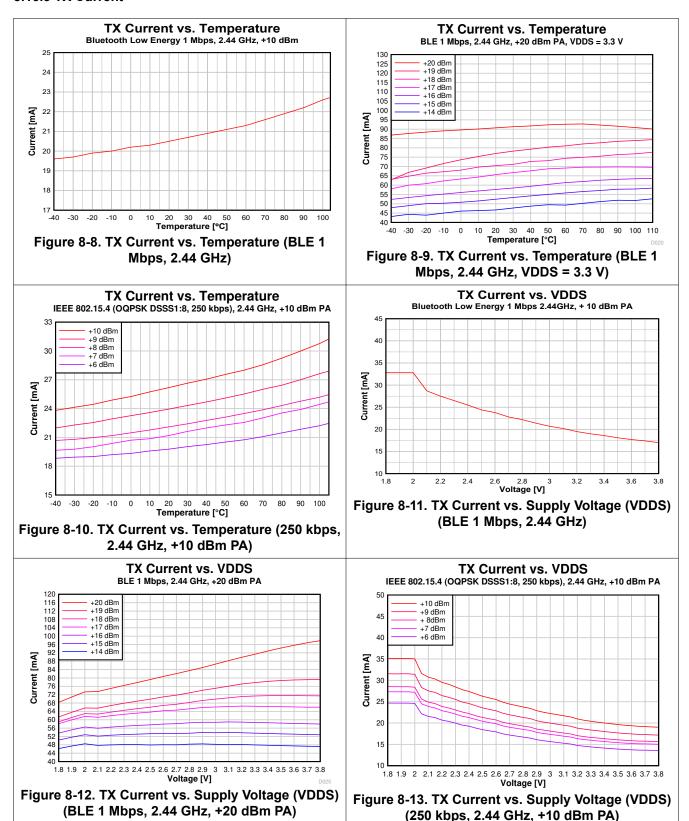




Table 8-1. Typical TX Current and Output Power, regular PA

CC2651P3 at 2.4 GHz, VDDS = 3.0 V (Measured on CC2651-P3EM-7XD24-PA24)						
txPower	TX Power Setting (SmartRF Studio)	Typical Output Power [dBm]	Typical Current Consumption [mA]			
0x701F	5	5.5	12.5			
0x3A17	4	4.5	11.9			
0x3A64	3	3.1	11.2			
0x325F	2	2.0	10.8			
0x2C5C	1	1.3	10.5			
0x2659	0	0.4	10.2			
0x1697	-3	-2.8	9.4			
0x1693	-5	-4.8	8.9			
0x1292	-6	-5.4	8.8			
0xCD3	-9	-9.0	8.4			
0xAD1	-10	-10.4	8.2			
0xACF	-12	-12.0	8.1			
0x6CD	-15	-13.7	7.9			
0x6CA	-18	-16.8	7.7			
0x4C8	-20	-19.3	7.6			

Table 8-2. Typical TX Current and Output Power, high power PA, 10 dBm mode

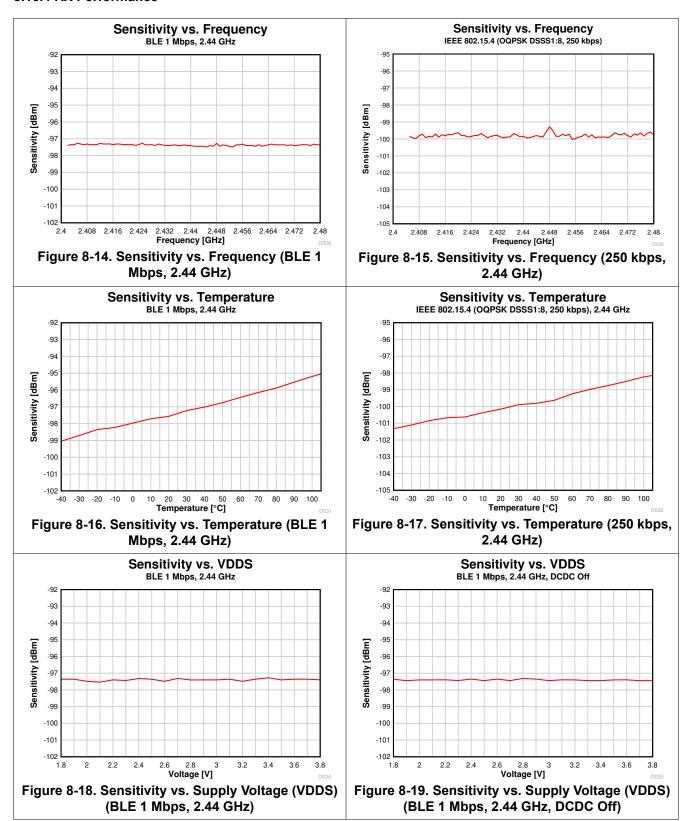
CC2651P3 at 2.4 GHz, VDDS = 3.0 V (Measured on CC261-P3EM-5XS24-PA24_10dBm)						
txPower	TX Power Setting (SmartRF Studio)	Typical Output Power [dBm]	Typical Current Consumption [mA]			
0x14395A	10	10.1	23.6			
0x142F55	9	9.0	22.1			
0x62F35	8	7.8	21.1			
0x63930	7	6.9	20.1			
0x6292B	6	5.9	19.1			

Table 8-3. Typical TX Current and Output Power, high power PA, 20 dBm mode

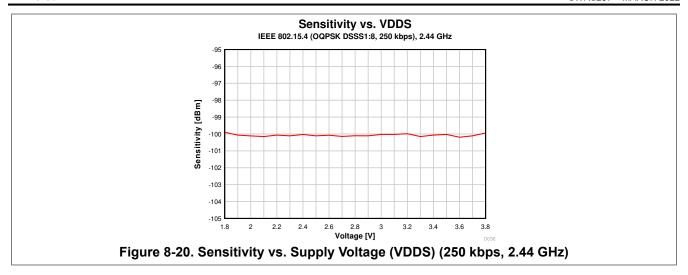
	CC2651P3 at 2.4 GHz, VDDS = 3.3 V (Measured on CC2651-P3EM-7XD24-PA24)						
txPower	TX Power Setting (SmartRF Studio)	Typical Output Power [dBm]	Typical Current Consumption [mA]				
0x3F75F5	20	20.0	100.1				
0x3F61E2	19	19.4	91.1				
0x3047E0	18	19.0	86.4				
0x1B4FE5	17	18.1	78.3				
0x1B39DE	16	17.3	71.8				
0x1B2FDA	15	16.7	67.1				
0x1B27D6	14	15.9	61.8				



8.16.4 RX Performance

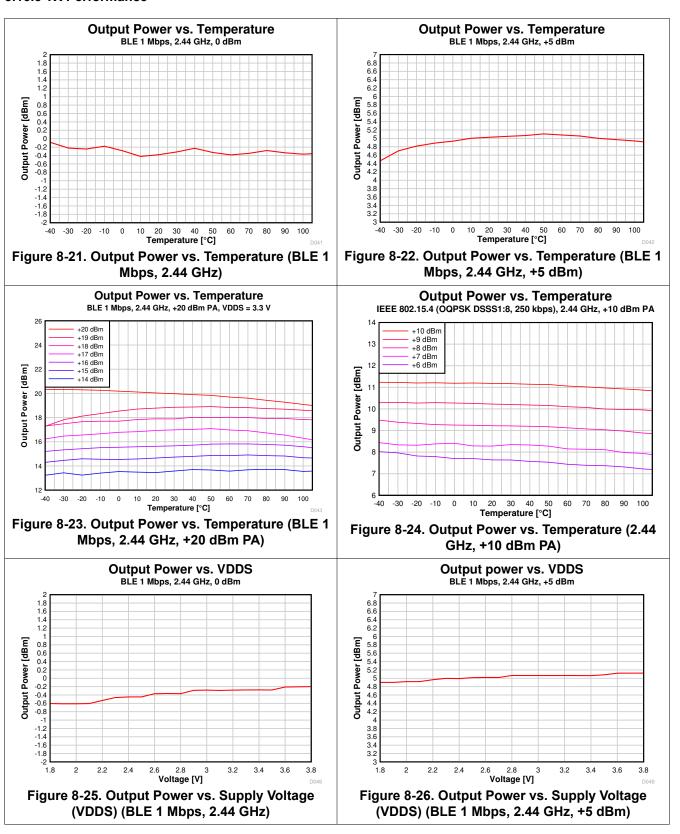








8.16.5 TX Performance



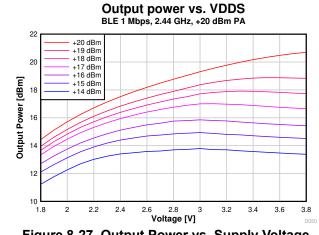


Figure 8-27. Output Power vs. Supply Voltage (VDDS) (BLE 1 Mbps, 2.44 GHz, +20 dBm PA)

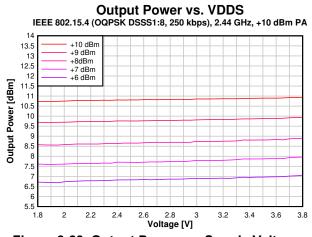


Figure 8-28. Output Power vs. Supply Voltage (VDDS) (2.44 GHz, +10 dBm PA)

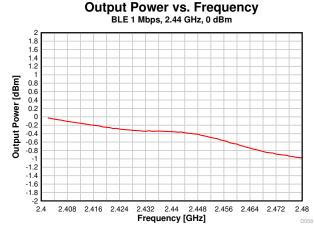


Figure 8-29. Output Power vs. Frequency (BLE 1 Mbps, 2.44 GHz)

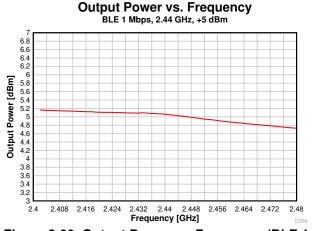
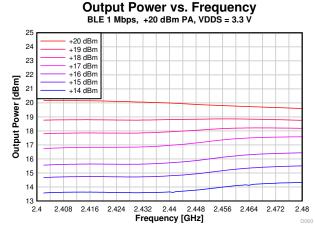
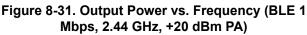


Figure 8-30. Output Power vs. Frequency (BLE 1 Mbps, 2.44 GHz, +5 dBm)





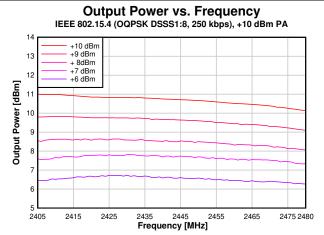
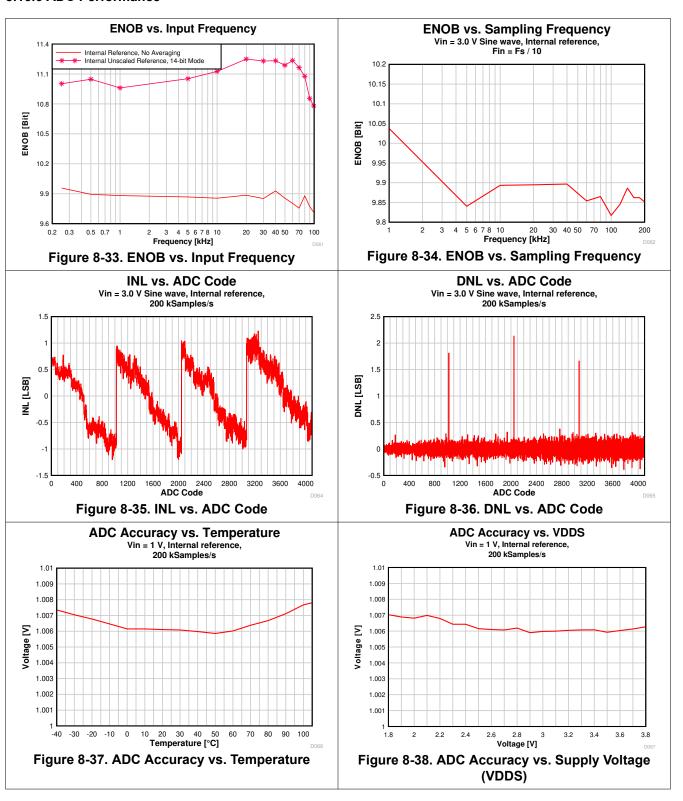


Figure 8-32. Output Power vs. Frequency (250 kbps, +10 dBm PA)



8.16.6 ADC Performance





9 Detailed Description

9.1 Overview

Section 4 shows the core modules of the CC2651P3 device.

9.2 System CPU

The CC2651P3 SimpleLink[™] Wireless MCU contains an Arm[®] Cortex[®]-M4 system CPU, which runs the application and the higher layers of radio protocol stacks.

The system CPU is the foundation of a high-performance, low-cost platform that meets the system requirements of minimal memory implementation, and low-power consumption, while delivering outstanding computational performance and exceptional system response to interrupts.

Its features include the following:

- ARMv7-M architecture optimized for small-footprint embedded applications
- Arm Thumb®-2 mixed 16- and 32-bit instruction set delivers the high performance expected of a 32-bit Arm
 core in a compact memory size
- Fast code execution permits increased sleep mode time
- Deterministic, high-performance interrupt handling for time-critical applications
- Single-cycle multiply instruction and hardware divide
- · Hardware division and fast digital-signal-processing oriented multiply accumulate
- · Saturating arithmetic for signal processing
- Full debug with data matching for watchpoint generation
 - Data Watchpoint and Trace Unit (DWT)
 - JTAG Debug Access Port (DAP)
 - Flash Patch and Breakpoint Unit (FPB)
- · Trace support reduces the number of pins required for debugging and tracing
 - Instrumentation Trace Macrocell Unit (ITM)
 - Trace Port Interface Unit (TPIU) with asynchronous serial wire output (SWO)
- · Optimized for single-cycle flash memory access
- Tightly connected to 8-KB 4-way random replacement cache for minimal active power consumption and wait states
- Ultra-low-power consumption with integrated sleep modes
- 48 MHz operation
- 1.25 DMIPS per MHz

9.3 Radio (RF Core)

The RF Core is a highly flexible and future proof radio module which contains an Arm Cortex-M0 processor that interfaces the analog RF and base-band circuitry, handles data to and from the system CPU side, and assembles the information bits in a given packet structure. The RF core offers a high level, command-based API to the main CPU that configurations and data are passed through. The Arm Cortex-M0 processor is not programmable by customers and is interfaced through the TI-provided RF driver that is included with the SimpleLink Software Development Kit (SDK).

The RF core can autonomously handle the time-critical aspects of the radio protocols, thus offloading the main CPU, which reduces power and leaves more resources for the user application. Several signals are also available to control external circuitry such as RF switches or range extenders autonomously.

The various physical layer radio formats are partly built as a software defined radio where the radio behavior is either defined by radio ROM contents or by non-ROM radio formats delivered in form of firmware patches with the SimpleLink SDKs. This allows the radio platform to be updated for support of future versions of standards even with over-the-air (OTA) updates while still using the same silicon.

9.3.1 Bluetooth 5.2 Low Energy

The RF Core offers full support for Bluetooth 5.2 Low Energy, including the high-sped 2-Mbps physical layer and the 500-kbps and 125-kbps long range PHYs (Coded PHY) through the TI provided Bluetooth 5.2 stack or through a high-level Bluetooth API.

The new high-speed mode allows data transfers up to 2 Mbps, twice the speed of Bluetooth 4.2 and five times the speed of Bluetooth 4.0, without increasing power consumption. In addition to faster speeds, this mode offers significant improvements for energy efficiency and wireless coexistence with reduced radio communication time.

Bluetooth 5.2 also enables unparalleled flexibility for adjustment of speed and range based on application needs, which capitalizes on the high-speed or long-range modes respectively. Data transfers are now possible at 2 Mbps, enabling development of applications using voice, audio, imaging, and data logging that were not previously an option using Bluetooth low energy. With high-speed mode, existing applications deliver faster responses, richer engagement, and longer battery life. Bluetooth 5.2 enables fast, reliable firmware updates.

9.3.2 802.15.4 (Zigbee and 6LoWPAN)

Through a dedicated IEEE radio API, the RF Core supports the 2.4-GHz IEEE 802.15.4-2011 physical layer (2 Mchips per second Offset-QPSK with DSSS 1:8), used in Zigbee and 6LoWPAN protocols. TI provides royalty-free protocol stacks for Zigbee as part of the SimpleLink SDK, enabling a robust end-to-end solution.

Product Folder Links: CC2651P3



9.4 Memory

The up to 352-KB nonvolatile (Flash) memory provides storage for code and data. The flash memory is in-system programmable and erasable. The last flash memory sector must contain a Customer Configuration section (CCFG) that is used by boot ROM and TI provided drivers to configure the device. This configuration is done through the ccfg.c source file that is included in all TI provided examples.

The ultra-low leakage system static RAM (SRAM) is a single 32-KB block and can be used for both storage of data and execution of code. Retention of SRAM contents in Standby power mode is enabled by default and included in Standby mode power consumption numbers.

To improve code execution speed and lower power when executing code from nonvolatile memory, a 4-way nonassociative 8-KB cache is enabled by default to cache and prefetch instructions read by the system CPU. The cache can be used as a general-purpose RAM by enabling this feature in the Customer Configuration Area (CCFG).

The ROM contains a serial (SPI and UART) bootloader that can be used for initial programming of the device.



9.5 Cryptography

The CC2651P3 device comes with a wide set of cryptography-related hardware accelerators, reducing code footprint and execution time for cryptographic operations. It also has the benefit of being lower power and improves availability and responsiveness of the system because the cryptography operations run in a background hardware thread.

The hardware accelerator modules are:

- True Random Number Generator (TRNG) module provides a true, nondeterministic noise source for the purpose of generating keys, initialization vectors (IVs), and other random number requirements. The TRNG is built on 24 ring oscillators that create unpredictable output to feed a complex nonlinear-combinatorial circuit.
- Advanced Encryption Standard (AES) with 128 bit key lengths

Together with the hardware accelerator module, a large selection of open-source cryptography libraries provided with the Software Development Kit (SDK), this allows for secure and future proof IoT applications to be easily built on top of the platform. The TI provided cryptography drivers are:

- Key Agreement Schemes
 - Elliptic curve Diffie
 – Hellman with static or ephemeral keys (ECDH and ECDHE)
- Signature Generation
 - Elliptic curve Diffie-Hellman Digital Signature Algorithm (ECDSA)
- Curve Support
 - Short Weierstrass form (full hardware support), such as:
 - NIST-P256
 - Montgomery form (hardware support for multiplication), such as:
 - Curve25519
- Hash
 - SHA256
- MACs
 - HMAC with SHA256
 - AES CBC-MAC
- Block ciphers
 - AESECB
 - AESCBC
 - AESCTR
- Authenticated Encryption
 - AESCCM
- Random number generation
 - True Random Number Generator
 - AES CTR DRBG



9.6 Timers

A large selection of timers are available as part of the CC2651P3 device. These timers are:

Real-Time Clock (RTC)

A 70-bit 3-channel timer running on the 32 kHz low frequency system clock (SCLK_LF) This timer is available in all power modes except Shutdown. The timer can be calibrated to compensate for frequency drift when using the LF RCOSC as the low frequency system clock. If an external LF clock with frequency different from 32.768 kHz is used, the RTC tick speed can be adjusted to compensate for this. When using TI-RTOS, the RTC is used as the base timer in the operating system and should thus only be accessed through the kernel APIs such as the Clock module. By default, the RTC halts when a debugger halts the device.

General Purpose Timers (GPTIMER)

The four flexible GPTIMERs can be used as either 4× 32 bit timers or 8× 16 bit timers, all running on up to 48 MHz. Each of the 16- or 32-bit timers support a wide range of features such as one-shot or periodic counting, pulse width modulation (PWM), time counting between edges and edge counting. The inputs and outputs of the timer are connected to the device event fabric, which allows the timers to interact with signals such as GPIO inputs, other timers, DMA and ADC. The GPTIMERs are available in Active and Idle power modes.

Radio Timer

A multichannel 32-bit timer running at 4 MHz is available as part of the device radio. The radio timer is typically used as the timing base in wireless network communication using the 32-bit timing word as the network time. The radio timer is synchronized with the RTC by using a dedicated radio API when the device radio is turned on or off. This ensures that for a network stack, the radio timer seems to always be running when the radio is enabled. The radio timer is in most cases used indirectly through the trigger time fields in the radio APIs and should only be used when running the accurate 48 MHz high frequency crystal is the source of SCLK HF.

Watchdog timer

The watchdog timer is used to regain control if the system operates incorrectly due to software errors. It is typically used to generate an interrupt to and reset of the device for the case where periodic monitoring of the system components and tasks fails to verify proper functionality. The watchdog timer runs on a 1.5 MHz clock rate and cannot be stopped once enabled. The watchdog timer pauses to run in Standby power mode and when a debugger halts the device.

Copyright © 2022 Texas Instruments Incorporated



9.7 Serial Peripherals and I/O

The SSI is a synchronous serial interface that is compatible with SPI, MICROWIRE, and TI's synchronous serial interfaces. The SSI support both SPI master and slave up to 4 MHz. The SSI module support configurable phase and polarity.

The UART implement universal asynchronous receiver and transmitter functions. It support flexible baud-rate generation up to a maximum of 3 Mbps.

The I²S interface is used to handle digital audio and can also be used to interface pulse-density modulation microphones (PDM).

The I^2C interface is also used to communicate with devices compatible with the I^2C standard. The I^2C interface can handle 100 kHz and 400 kHz operation, and can serve as both master and slave.

The I/O controller (IOC) controls the digital I/O pins and contains multiplexer circuitry to allow a set of peripherals to be assigned to I/O pins in a flexible manner. All digital I/Os are interrupt and wake-up capable, have a programmable pullup and pulldown function, and can generate an interrupt on a negative or positive edge (configurable). When configured as an output, pins can function as either push-pull or open-drain. Five GPIOs have high-drive capabilities, which are marked in **bold** in Section 7. All digital peripherals can be connected to any digital pin on the device.

For more information, see the CC13x1x3, CC26x1x3 SimpleLink™ Wireless MCU Technical Reference Manual.

9.8 Battery and Temperature Monitor

A combined temperature and battery voltage monitor is available in the CC2651P3 device. The battery and temperature monitor allows an application to continuously monitor on-chip temperature and supply voltage and respond to changes in environmental conditions as needed. The module contains window comparators to interrupt the system CPU when temperature or supply voltage go outside defined windows. These events can also be used to wake up the device from Standby mode through the Always-On (AON) event fabric.

9.9 µDMA

The device includes a direct memory access (μ DMA) controller. The μ DMA controller provides a way to offload data-transfer tasks from the system CPU, thus allowing for more efficient use of the processor and the available bus bandwidth. The μ DMA controller can perform a transfer between memory and peripherals. The μ DMA controller has dedicated channels for each supported on-chip module and can be programmed to automatically perform transfers between peripherals and memory when the peripheral is ready to transfer more data.

Some features of the µDMA controller include the following (this is not an exhaustive list):

- Highly flexible and configurable channel operation of up to 32 channels
- Transfer modes: memory-to-memory, memory-to-peripheral, peripheral-to-memory, and peripheral-to-peripheral
- Data sizes of 8, 16, and 32 bits
- · Ping-pong mode for continuous streaming of data

9.10 Debug

The on-chip debug support is done through a dedicated cJTAG (IEEE 1149.7) or JTAG (IEEE 1149.1) interface. The device boots by default into cJTAG mode and must be reconfigured to use 4-pin JTAG.

Submit Document Feedback

Copyright © 2022 Texas Instruments Incorporated

Off

Off

On

Off

Off

Off

Wake-up on RTC

Wake-up on pin edge

Wake-up on reset pin

Power-on reset (POR)

Watchdog timer (WDT)

Brownout detector (BOD)

9.11 Power Management

To minimize power consumption, the CC2651P3 supports a number of power modes and power management features (see Table 9-1).

SOFTWARE CONFIGURABLE POWER MODES **RESET PIN** MODE **HELD ACTIVE** IDLE **STANDBY SHUTDOWN** CPU Off Active Off Off Off Flash On Available Off Off Off SRAM On On Retention Off Off **Supply System Duty Cycled** Off Off On On Register and CPU retention Full **Partial** Full No No SRAM retention Full Full Full No No 48 MHz high-speed clock XOSC HF or XOSC HF or Off Off Off (SCLK HF) RCOSC HF RCOSC HF 32 kHz low-speed clock XOSC LF or XOSC LF or XOSC LF or Off Off (SCLK LF) RCOSC LF RCOSC LF RCOSC LF Peripherals Available Available Off Off Off

Available

Available

On

On

On

Available

Available

Available

On

Duty Cycled

On

Paused

Off

Available

On

Off

Off

Off

Available

Available

On

On

On

Available

Table 9-1. Power Modes

In **Active** mode, the application system CPU is actively executing code. Active mode provides normal operation of the processor and all of the peripherals that are currently enabled. The system clock can be any available clock source (see Table 9-1).

In **Idle** mode, all active peripherals can be clocked, but the Application CPU core and memory are not clocked and no code is executed. Any interrupt event brings the processor back into active mode.

In **Standby** mode, only the always-on (AON) domain is active. An external wake-up event or RTC event is required to bring the device back to active mode. MCU peripherals with retention do not need to be reconfigured when waking up again, and the CPU continues execution from where it went into standby mode. All GPIOs are latched in standby mode.

In **Shutdown** mode, the device is entirely turned off (including the AON domain), and the I/Os are latched with the value they had before entering shutdown mode. A change of state on any I/O pin defined as a *wake from shutdown pin* wakes up the device and functions as a reset trigger. The CPU can differentiate between reset in this way and reset-by-reset pin or power-on reset by reading the reset status register. The only state retained in this mode is the latched I/O state and the flash memory contents.

Note

The power, RF and clock management for the CC2651P3 device require specific configuration and handling by software for optimized performance. This configuration and handling is implemented in the TI-provided drivers that are part of the CC2651P3 software development kit (SDK). Therefore, TI highly recommends using this software framework for all application development on the device. The complete SDK with TI-RTOS (optional), device drivers, and examples are offered free of charge in source code.



9.12 Clock Systems

The CC2651P3 device has several internal system clocks.

The 48 MHz SCLK_HF is used as the main system (MCU and peripherals) clock. This can be driven by the internal 48 MHz RC Oscillator (RCOSC_HF) or an external 48 MHz crystal (XOSC_HF). Radio operation requires an external 48 MHz crystal.

SCLK_LF is the 32.768 kHz internal low-frequency system clock. It can be used for the RTC and to synchronize the radio timer before or after Standby power mode. SCLK_LF can be driven by the internal 32.8 kHz RC Oscillator (RCOSC LF), a 32.768 kHz watch-type crystal, or a clock input on any digital IO.

When using a crystal or the internal RC oscillator, the device can output the 32 kHz SCLK_LF signal to other devices, thereby reducing the overall system cost.

9.13 Network Processor

Depending on the product configuration, the CC2651P3 device can function as a wireless network processor (WNP - a device running the wireless protocol stack with the application running on a separate host MCU), or as a system-on-chip (SoC) with the application and protocol stack running on the system CPU inside the device.

In the first case, the external host MCU communicates with the device using SPI or UART. In the second case, the application must be written according to the application framework supplied with the wireless protocol stack.

Submit Document Feedback

Copyright © 2022 Texas Instruments Incorporated



10 Application, Implementation, and Layout

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

For general design guidelines and hardware configuration guidelines, refer to CC13xx/CC26xx Hardware Configuration and PCB Design Considerations Application Report.

For optimum RF performance, especially when using the high-power PA, it is important to accurately follow the reference design with respect to component values and layout. Failure to do so may lead to reduced RF performance due to balun mismatch. The amplitude- and phase balance through the balun must be <1 dB and <6 degrees, respectively.

PCB stack-up is also critical for proper operation. The CC2651P3 EVMs and characterization boards use a finished thickness between the top layer (RF signals) and layer 2 (ground plane) of 175 μ m. It is very important to use the same substrate thickness, or slightly thicker, in an end product implementing the CC2651P3 device.

10.1 Reference Designs

The following reference designs should be followed closely when implementing designs using the CC2651P3 device.

Special attention must be paid to RF component placement, decoupling capacitors and DCDC regulator components, as well as ground connections for all of these.

CC26x1-P3EM-5XS24-PA24_10dBm Design Files

The CC26x1PEM-5XS24-PA24_10dBm reference design provides schematic, layout and production files for the characterization board used for deriving the performance number found in this document. This design is optimized for operating the high power PA at 10 dBm output power and is using a single-ended front-end configuration with external LNA bias for RX.

CC26x1-P3EM-7XD24-PA24 Design Files

The CC26x1-P3EM-7XD24-PA24 reference design provides schematic, layout and production files for the characterization board used for deriving the performance number found in this document. This design is configured for 20 dBm operation on the high output power PA.

LP-CC2651P3 Design Files

The CC2651P3 LaunchPad Design Files contain detailed schematics and layouts to build application specific boards using the CC2651P3 device.

Sub-1 GHz and 2.4 GHz Antenna Kit for LaunchPad™ Development Kit and SensorTag

The antenna kit allows real-life testing to identify the optimal antenna for your application. The antenna kit includes 16 antennas for frequencies from 169 MHz to 2.4 GHz, including:

- PCB antennas
- · Helical antennas
- · Chip antennas
- Dual-band antennas for 868 MHz and 915 MHz combined with 2.4 GHz

The antenna kit includes a JSC cable to connect to the Wireless MCU LaunchPad Development Kits and SensorTags.



11 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed as follows.

11.1 Device Nomenclature

To designate the stages in the product development cycle, TI assigns prefixes to all part numbers and/or date-code. Each device has one of three prefixes/identifications: X, P, or null (no prefix) (for example, XCC2651P3 is in preview; therefore, an X prefix/identification is assigned).

Device development evolutionary flow:

- **X** Experimental device that is not necessarily representative of the final device's electrical specifications and may not use production assembly flow.
- **P** Prototype device that is not necessarily the final silicon die and may not necessarily meet final electrical specifications.

null Production version of the silicon die that is fully qualified.

Support tool development evolutionary flow:

TMDX Development-support product that has not yet completed Texas Instruments internal qualification testing.

TMDS Fully-qualified development-support product.

X and P devices and TMDX development-support tools are shipped against the following disclaimer:

"Developmental product is intended for internal evaluation purposes."

Production devices and TMDS development-support tools have been characterized fully, and the quality and reliability of the device have been demonstrated fully. Tl's standard warranty applies.

Predictions show that prototype devices (X or P) have a greater failure rate than the standard production devices. Texas Instruments recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

TI device nomenclature also includes a suffix with the device family name. This suffix indicates the package type (for example, *RGZ*).

For orderable part numbers of *CC2651P3* devices in the RGZ (7-mm x 7-mm) package type, see the *Package Option Addendum* of this document, the Device Information in Section 3, the TI website (www.ti.com), or contact your TI sales representative.

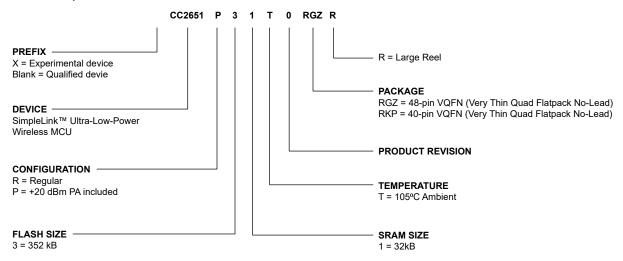


Figure 11-1. Device Nomenclature



11.2 Tools and Software

The CC2651P3 device is supported by a variety of software and hardware development tools.

Development Kit

CC2651P3 LaunchPad™ Development Kit

The CC2651P3 LaunchPad[™] Development Kit enables development of high-performance wireless applications that benefit from low-power operation. The kit features the CC2651P3 SimpleLink Wireless MCU, which allows you to quickly evaluate and prototype 2.4-GHz wireless applications such as Bluetooth 5 Low Energy, Zigbee and Thread, plus combinations of these. The kit works with the LaunchPad ecosystem, easily enabling additional functionality like sensors, display and more.

Software

SimpleLink™ CC13XX-CC26XX SDK

The SimpleLink CC13xx and CC26xx Software Development Kit (SDK) provides a complete package for the development of wireless applications on the CC13XX / CC26XX family of devices. The SDK includes a comprehensive software package for the CC2651P3 device, including the following protocol stacks:

- Bluetooth Low Energy 4 and 5.2
- Thread (based on OpenThread)
- · Zigbee 3.0
- Wi-SUN®
- TI 15.4-Stack an IEEE 802.15.4-based star networking solution for Sub-1 GHz and 2.4 GHz
- Proprietary RF a large set of building blocks for building proprietary RF software
- Multiprotocol support concurrent operation between stacks using the Dynamic Multiprotocol Manager (DMM)

The SimpleLink CC13XX-CC26XX SDK is part of TI's SimpleLink MCU platform, offering a single development environment that delivers flexible hardware, software and tool options for customers developing wired and wireless applications. For more information about the SimpleLink MCU Platform, visit http://www.ti.com/simplelink.



Development Tools

Code Composer Studio™ Integrated Development Environment (IDE)

Code Composer Studio is an integrated development environment (IDE) that supports TI's Microcontroller and Embedded Processors portfolio. Code Composer Studio comprises a suite of tools used to develop and debug embedded applications. It includes an optimizing C/C++ compiler, source code editor, project build environment, debugger, profiler, and many other features. The intuitive IDE provides a single user interface taking you through each step of the application development flow. Familiar tools and interfaces allow users to get started faster than ever before. Code Composer Studio combines the advantages of the Eclipse® software framework with advanced embedded debug capabilities from TI resulting in a compelling feature-rich development environment for embedded developers.

CCS has support for all SimpleLink Wireless MCUs and includes support for EnergyTrace™ software (application energy usage profiling). A real-time object viewer plugin is available for TI-RTOS, part of the SimpleLink SDK.

Code Composer Studio is provided free of charge when used in conjunction with the XDS debuggers included on a LaunchPad Development Kit.

Code Composer Studio™ Cloud IDE

Code Composer Studio (CCS) Cloud is a web-based IDE that allows you to create, edit and build CCS and Energia[™] projects. After you have successfully built your project, you can download and run on your connected LaunchPad. Basic debugging, including features like setting breakpoints and viewing variable values is now supported with CCS Cloud.

IAR Embedded Workbench® for Arm®

IAR Embedded Workbench[®] is a set of development tools for building and debugging embedded system applications using assembler, C and C++. It provides a completely integrated development environment that includes a project manager, editor, and build tools. IAR has support for all SimpleLink Wireless MCUs. It offers broad debugger support, including XDS110, IAR I-jet™ and Segger J-Link™. A real-time object viewer plugin is available for TI-RTOS, part of the SimpleLink SDK. IAR is also supported out-of-the-box on most software examples provided as part of the SimpleLink SDK.

A 30-day evaluation or a 32 KB size-limited version is available through iar.com.

SmartRF™ Studio

SmartRF™ Studio is a Windows® application that can be used to evaluate and configure SimpleLink Wireless MCUs from Texas Instruments. The application will help designers of RF systems to easily evaluate the radio at an early stage in the design process. It is especially useful for generation of configuration register values and for practical testing and debugging of the RF system. SmartRF Studio can be used either as a standalone application or together with applicable evaluation boards or debug probes for the RF device. Features of the SmartRF Studio include:

- Link tests send and receive packets between nodes
- Antenna and radiation tests set the radio in continuous wave TX and RX states
- Export radio configuration code for use with the TI SimpleLink SDK RF driver
- Custom GPIO configuration for signaling and control of external switches

CCS UniFlash

CCS UniFlash is a standalone tool used to program on-chip flash memory on TI MCUs. UniFlash has a GUI, command line, and scripting interface. CCS UniFlash is available free of charge.

11.2.1 SimpleLink™ Microcontroller Platform

The SimpleLink microcontroller platform sets a new standard for developers with the broadest portfolio of wired and wireless Arm[®] MCUs (System-on-Chip) in a single software development environment. Delivering flexible hardware, software and tool options for your IoT applications. Invest once in the SimpleLink software development kit and use throughout your entire portfolio. Learn more on ti.com/simplelink.

11.3 Documentation Support

To receive notification of documentation updates on data sheets, errata, application notes and similar, navigate to the device product folder on ti.com/product/CC2651P3. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

The current documentation that describes the MCU, related peripherals, and other technical collateral is listed as follows.

TI Resource Explorer

TI Resource Explorer

Software examples, libraries, executables, and documentation are available for your device and development board.

Errata

CC2651P3 Silicon Errata

The silicon errata describes the known exceptions to the functional specifications for each silicon revision of the device and description on how to recognize a device revision.

Application Reports

All application reports for the CC2651P3 device are found on the device product folder at: ti.com/product/CC2651P3/#tech-docs.

Technical Reference Manual (TRM)

CC13x1x, CC26x1x SimpleLink™ Wireless MCU TRM

The TRM provides a detailed description of all modules and peripherals available in the device family.

11.4 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

11.5 Trademarks

SimpleLink[™], LaunchPad[™], Code Composer Studio[™], EnergyTrace[™], and TI E2E[™] are trademarks of Texas Instruments.

I-jet[™] is a trademark of IAR Systems AB.

J-Link[™] is a trademark of SEGGER Microcontroller Systeme GmbH.

Arm® and Cortex® are registered trademarks of Arm Limited (or its subsidiaries) in the US and/or elsewhere.

CoreMark® is a registered trademark of Embedded Microprocessor Benchmark Consortium Corporation.

Zigbee® is a registered trademark of Zigbee Alliance Inc.

Bluetooth® is a registered trademark of Bluetooth SIG Inc.

Arm Thumb® is a registered trademark of Arm Limited (or its subsidiaries).

Wi-SUN® is a registered trademark of Wi-SUN Alliance Inc.

Eclipse® is a registered trademark of Eclipse Foundation.

IAR Embedded Workbench® is a registered trademark of IAR Systems AB.



Windows[®] is a registered trademark of Microsoft Corporation. All trademarks are the property of their respective owners.

11.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

11.7 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

Submit Document Feedback

Copyright © 2022 Texas Instruments Incorporated

12 Mechanical, Packaging, and Orderable Information





7-Oct-2025 www.ti.com

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
CC2651P31T0RGZR	Active	Production	VQFN (RGZ) 48	2500 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 105	CC2651 P31
CC2651P31T0RGZR.A	Active	Production	VQFN (RGZ) 48	2500 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 105	CC2651 P31
CC2651P31T0RGZR.B	Active	Production	VQFN (RGZ) 48	2500 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 105	CC2651 P31
CC2651P31T0RKPR	Active	Production	VQFN (RKP) 40	3000 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 105	CC2651 P31
CC2651P31T0RKPR.A	Active	Production	VQFN (RKP) 40	3000 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 105	CC2651 P31
CC2651P31T0RKPR.B	Active	Production	VQFN (RKP) 40	3000 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 105	CC2651 P31
CC2651P31T0RKPRG4	Active	Production	VQFN (RKP) 40	3000 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 105	CC2651 P31
CC2651P31T0RKPRG4.A	Active	Production	VQFN (RKP) 40	3000 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 105	CC2651 P31
CC2651P31T0RKPRG4.B	Active	Production	VQFN (RKP) 40	3000 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 105	CC2651 P31

⁽¹⁾ Status: For more details on status, see our product life cycle.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.



PACKAGE OPTION ADDENDUM

www.ti.com 7-Oct-2025

(6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 18-Jun-2025

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CC2651P31T0RGZR	VQFN	RGZ	48	2500	330.0	16.4	7.3	7.3	1.1	12.0	16.0	Q2
CC2651P31T0RKPR	VQFN	RKP	40	3000	330.0	12.4	5.3	5.3	1.1	8.0	12.0	Q2
CC2651P31T0RKPRG4	VQFN	RKP	40	3000	330.0	12.4	5.3	5.3	1.1	8.0	12.0	Q2

www.ti.com 18-Jun-2025



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CC2651P31T0RGZR	VQFN	RGZ	48	2500	367.0	367.0	35.0
CC2651P31T0RKPR	VQFN	RKP	40	3000	367.0	367.0	35.0
CC2651P31T0RKPRG4	VQFN	RKP	40	3000	367.0	367.0	35.0

7 x 7, 0.5 mm pitch

PLASTIC QUADFLAT PACK- NO LEAD



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4224671/A



PLASTIC QUADFLAT PACK- NO LEAD



NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC QUADFLAT PACK- NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUADFLAT PACK- NO LEAD



NOTES: (continued)

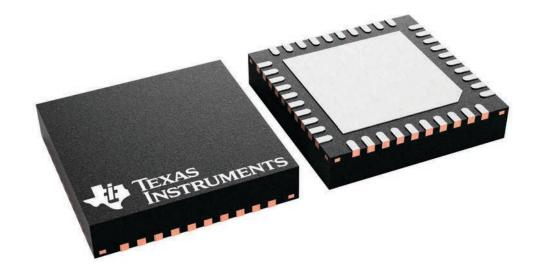
6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



5 x 5, 0.4 mm pitch

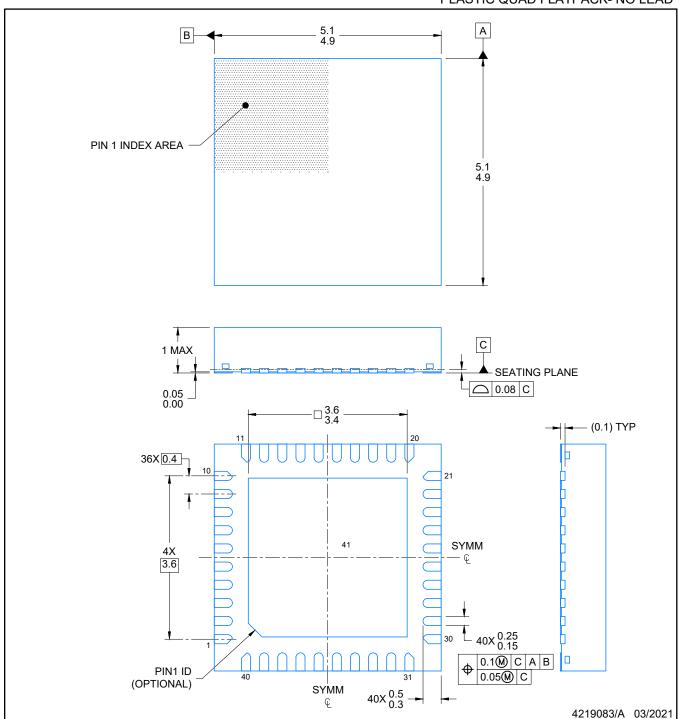
PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



Instruments www.ti.com

PLASTIC QUAD FLATPACK- NO LEAD

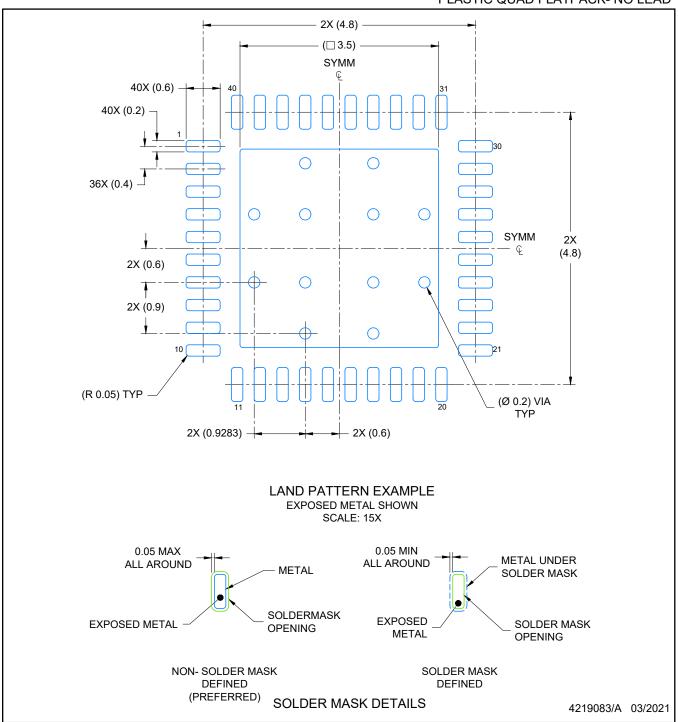


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC QUAD FLATPACK- NO LEAD

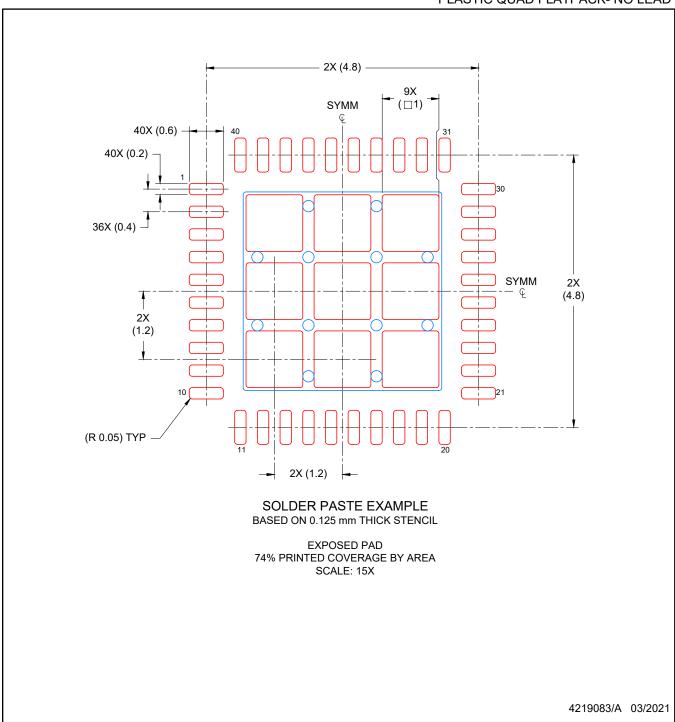


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLATPACK- NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2025. Texas Instruments Incorporated